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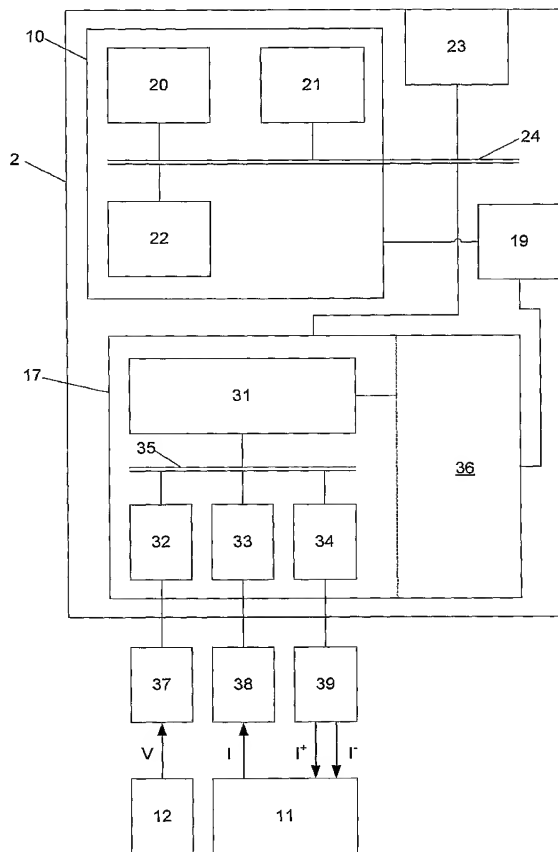
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**(54) Title:** MONITORING SYSTEM



**(57) Abstract:** Apparatus for performing impedance measurements on a subject. The apparatus includes a first processing system for determining an impedance measurement procedure and determining instructions corresponding to the measurement procedure. A second processing system is provided for receiving the instructions, using the instructions to generate control signals, with the control signals being used to apply one or more signals to the subject. The second processing system then receives first data indicative of the one or more signals applied to the subject, second data indicative of one or more signals measured across the subject and performs at least preliminary processing of the first and second data to thereby allow impedance values to be determined.

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## **MONITORING SYSTEM**

### **Background of the Invention**

The present invention relates to a method and apparatus for monitoring biological parameters, and in particular to apparatus for making impedance measurements.

### **5 Description of the Prior Art**

The reference in this specification to any prior publication (or information derived from it), or to any matter which is known, is not, and should not be taken as an acknowledgment or admission or any form of suggestion that the prior publication (or information derived from it) or known matter forms part of the common general knowledge in the field of endeavour to which this specification relates.

10 One existing technique for determining biological parameters relating to a subject, such as cardiac function, involves the use of bioelectrical impedance. This involves measuring the electrical impedance of a subject's body using a series of electrodes placed on the skin surface. Changes in electrical impedance at the body's surface are used to determine parameters, such as changes in fluid levels, associated with the cardiac cycle or oedema.

15 Accordingly, complex signal processing is required to ensure measurements can be interpreted.

Typically devices for achieving this utilise custom hardware configurations that are application specific. As a result, the devices can typically only be used in a limited range of circumstances.

### **Summary of the Present Invention**

In a first broad form the present invention provides apparatus for performing impedance  
20 measurements on a subject, the apparatus including:

- a) a first processing system for:
  - i) determining an impedance measurement procedure; and,
  - ii) selecting instructions corresponding to the measurement procedure; and,

- b) a second processing system for:

- 25 i) generating, using the instructions, control signals, the control signals being used to apply one or more signals to the subject;
- ii) receiving an indication of the one or more signals applied to the subject;
- iii) receiving an indication of one or more signals measured across the subject;
- iv) performing, using the instructions, at least preliminary processing of the indications to  
30 thereby allow impedance values to be determined.

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Typically the method includes, transferring the instructions from the first processing system to the second processing system.

Typically the method includes, selecting the instructions using configuration data.

Typically the method includes, receiving the configuration data from a remote processing system.

5 Typically the instructions are in the form of at least one of:

- a) firmware; and,
- b) embedded systems.

Typically the second processing system is an FPGA.

10 Typically the apparatus includes an input device, and wherein the first processing system is coupled to the input device to thereby determine the impedance measurement procedure in accordance with input commands from an operator.

Typically the first processing system includes a store for storing at least one profile, the at least one profile representing a predetermined impedance measurement procedure.

15 Typically the control signals represent a sequence of predetermined electrical signals, the sequence being dependent on the selected impedance measurement type.

Typically the apparatus includes:

- a) a current ADC for:
  - i) receiving signals from a current circuit; and,
  - ii) providing the indication of the one or more signals applied to the subject to the second
- 20 b) a voltage ADC for:
  - i) receiving signals from a voltage circuit; and,
  - ii) providing the indication of the one or more signals measured from the subject to the second processing system.

25 Typically the apparatus includes at least one buffer circuit for:

- a) receiving voltage signals from a voltage electrode;
- b) filtering and amplifying the voltage signals; and,
- c) transferring the filtered and amplified voltage signals to the voltage ADC via a differential amplifier.

30 Typically the apparatus includes a current source circuit for:

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- a) receiving one or more control signals;
- b) filtering and amplifying the control signals to thereby generate one or more current signals;
- c) applying the current signals to a current electrode; and,
- d) transferring an indication of the applied signals to the current ADC.

5 Typically the apparatus includes a control signal DAC for:

- a) receiving the control signals from the second processing system; and,
- b) providing analogue control signals to a current circuit to thereby cause one or more current signals to be applied to the subject in accordance with the control signals.

10 Typically the second processing system is formed from first and second processing system portions, the first and second processing system portions being electrically isolated to thereby electrically isolate the subject from the first processing system.

Typically the apparatus includes:

- a) a measuring device including at least the first processing system; and,
  - b) one or more subject units, each subject unit including at least part of the second processing system.
- 15

Typically the apparatus includes at least two current electrodes for applying current signals to the subject, and a switch connected to the current electrodes for discharging the subject prior to measuring the induced voltage.

Typically the apparatus includes a housing having:

- a) a display;
  - b) a first circuit board for mounting at least one of the processing systems;
  - c) a second circuit board for mounting at least one of an ADC and a DAC; and,
  - d) a third circuit board for mounting a power supply.
- 20

25 Typically the housing is formed from at least one of a mu-metal and aluminium with added magnesium, to thereby provide electrical/magnetic shielding.

Typically the apparatus includes multiple channels, each channel being for performing impedance measurements using a respective set of electrodes.

Typically the apparatus is for:

- a) determining an electrode identifier associated with at least one electrode provided on the subject;
- 30

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- b) determining, using the electrode identifier, an electrode position indicative of the position of the at least one electrode on the subject; and,
- c) performing at least one impedance measurement using the electrode position.

Typically the apparatus is for:

- 5 a) determining a parameter associated with at least one electrode lead; and,
- b) causing at least one impedance measurement to be performed using the determined parameter.

Typically the apparatus is for:

- a) receiving configuration data, the configuration data being indicative of at least one feature;
- 10 b) determining, using the configuration data, instructions representing the at least one feature; and,
- c) causing, using the instructions, at least one of:
  - i) at least one impedance measurement to be performed; and,
  - ii) at least one impedance measurement to be analysed.

15 Typically the apparatus is for:

- a) causing a first signal to be applied to the subject;
- b) determining at least one parameter relating to at least one second signal measured across the subject;
- c) comparing the at least one parameter to at least one threshold; and,
- 20 d) depending on the results of the comparison, selectively repeating steps (a) to (d) using a first signal having an increased magnitude.

In a second broad form the present invention provides a method of performing impedance measurements on a subject, the method including:

- a) using a first processing system for:
  - 25 i) determining an impedance measurement procedure; and,
  - ii) selecting instructions corresponding to the measurement procedure; and,
- b) using a second processing system for:
  - i) generating, using the instructions, control signals, the control signals being used to apply one or more signals to the subject;
  - 30 ii) receiving an indication of the one or more signals applied to the subject;
  - iii) receiving an indication of one or more signals measured across the subject;
  - iv) performing, using the instructions, at least preliminary processing of the first and second data to thereby allow impedance values to be determined.

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In a third broad form the present invention provides a method of diagnosing conditions in a subject, the method including, in a processing system:

- a) using a first processing system for:
  - i) determining an impedance measurement procedure; and,
  - 5 ii) selecting instructions corresponding to the measurement procedure; and,
- b) using a second processing system for:
  - i) generating, using the instructions, control signals, the control signals being used to apply one or more signals to the subject;
  - ii) receiving an indication of the one or more signals applied to the subject;
  - 10 iii) receiving an indication of one or more signals measured across the subject;
  - iv) performing, using the instructions, at least preliminary processing of the first and second data to thereby allow impedance values to be determined.

In a fourth broad form the present invention provides apparatus for connecting measurement apparatus to an electrode, the apparatus including:

- 15 a) a housing having a connector for coupling the housing to an electrode; and,
- b) a circuit mounted in the housing, the circuit being electrically coupled to the electrode using the connector, and being coupled to a lead, the circuit being for at least one of:
  - i) generating predetermined electrical signals in accordance with control signals received from the measurement apparatus;
  - 20 ii) providing an indication of electrical signals applied to the electrode; and,
  - iii) providing an indication of electrical signals measured at the electrode.

Typically the circuit is provided on a circuit board having an electrical contact, and wherein in use the connector urges at least part of the electrode into abutment with the electrical contact.

Typically the connector includes a biased arm.

- 25 Typically the circuit includes a buffer circuit for:
  - a) sensing voltage signals at the electrode;
  - b) filtering and amplifying the voltage signals; and,
  - c) transferring the filtered and amplified voltage signals to the measurement apparatus.

Typically the circuit includes a current source circuit for:

- 30 a) receiving one or more control signals;
- b) filtering and amplifying the control signals to thereby generate one or more current signals;
- c) applying the current signals to the electrode pad; and,
- d) transferring an indication of the applied signals to the measurement apparatus.

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Typically the apparatus further comprises an electrode, the electrode including:

- a) an electrode substrate; and,
- b) a conductive material for electrically coupling the electrode to the subject.

Typically the electrode substrate is electrically conductive, and wherein in use the connector couples  
5 the circuit to the electrode substrate.

Typically the housing includes curved edges.

Typically the housing is formed from a material that, at least one of:

- a) has a low coefficient of friction; and,
- b) is resilient.

10 In a fifth broad form the present invention provides a method of performing impedance measurements on a subject, the method including, in a processing system:

- a) determining an encoded value associated with at least one electrode lead; and,
- b) causing at least one impedance measurement to be performed using the encoded value.

Typically the encoded value is used for calibration.

15 Typically the encoded value is determined from a resistance value.

Typically the encoded value is indicative of an identity of the lead.

Typically the method includes, in the processing system, controlling the current applied to the subject using the determined resistance.

20 Typically the encoded value is a lead identifier, and wherein the method includes, in the processing system:

- a) determining, using the lead identifier, an impedance measurement procedure; and,
- b) causing the determined impedance measurement procedure to be performed.

Typically the method includes, in the processing system:

- a) comparing the determined identity to one or more predetermined identities; and,
- 25 b) determining the impedance of the subject in response to a successful comparison.

Typically the method includes, in the processing system:

- a) determining the lead identifier associated with the at least one electrode lead;
- b) determining, using the lead identifier, a lead usage;
- c) comparing the lead usage to a threshold; and,



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d) in accordance with the results of the comparison, at least one of:

- i) generating an alert;
- ii) terminating an impedance measurement procedure; and,
- iii) performing an impedance measurement procedure.

5 Typically the method includes, in the processing system, at least one of:

- a) processing electrical signals measured from the subject to thereby determine one or more impedance values; and,
- b) processing determined impedance values.

Typically the encoded value is stored in a store.

10 In a sixth broad form the present invention provides apparatus for performing impedance measurements on a subject, the apparatus including:

- a) at least one lead for connecting to electrodes coupled to the subject, the at least one lead including an encoded value; and,
- b) a processing system coupled to the at least one lead for:

- 15 i) determining the encoded value; and,
- c) causing at least one impedance measurement to be performed using the encoded value.

In a seventh broad form the present invention provides a method of performing impedance measurements on a subject, the method including, in a processing system:

- 20 a) determining an electrode identifier associated with at least one electrode provided on the subject;
- b) determining, using the electrode identifier, an electrode position indicative of the position of the at least one electrode on the subject; and,
- c) causing at least one impedance measurement to be performed using the electrode position.

25 Typically the impedance measurement is performed using at least four electrodes, each having a respective identifier, and wherein the method includes, in the processing system:

- a) determining an electrode identifier for each electrode;
- b) determining, using each electrode identifier, an electrode position for each electrode; and,
- c) performing at least one impedance measurement using the electrode positions.

Typically the method includes, in the processing system:

- 30 a) causing signals to be applied to at least two of the electrodes in accordance with the determined electrode positions; and,

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- b) causing signals to be measured from at least two of the electrodes in accordance with the determined electrode positions.

Typically the method includes, in the processing system, determining the electrode identifier for an electrode by selectively measuring the conductivity between one or more contacts provided on the electrode.

Typically the processing system is coupled to a signal generator and a sensor, and wherein the method includes, in the processing system:

- a) selectively interconnecting the signal generator and at least two electrode leads, to thereby allow signals to be applied to the subject; and,
- b) selectively interconnecting the sensor at least two electrode leads to thereby allow a signal to be measured from the subject.

Typically the method includes, in the processing system controlling a multiplexer to thereby selectively interconnect the leads and at least one of the signal generator and the sensor.

Typically the at least one electrode includes visual indicia indicative of the position of the at least one electrode on the subject.

In an eighth broad form the present invention provides apparatus for performing impedance measurements on a subject, the apparatus including a processing system for:

- a) determining an electrode identifier associated with at least one electrode provided on the subject;
- b) determining, using the electrode identifier, an electrode position indicative of the position of the at least one electrode on the subject; and,
- c) causing at least one impedance measurement to be performed using the electrode position.

In a ninth broad form the present invention provides a method for configuring a measuring device for measuring the impedance of a subject, the method including, in a processing system:

- a) receiving configuration data, the configuration data being indicative of at least one feature;
- b) determining, using the configuration data, instructions representing the at least one feature; and,
- c) causing, at least in part using the instructions, at least one of:
- i) impedance measurements to be performed; and,
- ii) analysis of impedance measurements.

Typically the configuration data includes the instructions.

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Typically the method includes, in the processing system:

- a) determining an indication of the at least one feature using the configuration data; and,
- b) determining the instructions using the indication of the at least one feature.

Typically the method includes, in the processing system, decrypting the received configuration data.

5 Typically the method includes, in the processing system:

- a) determining a device identifier associated with the measuring device;
- b) determining, using the device identifier, a key; and,
- c) decrypting the received configuration data using the key.

10 Typically the processing system includes first and second processing systems, and wherein the method includes:

- a) in the first processing system, selecting the instructions using the configuration data; and,
- b) in the second processing system, generating the control signals using selected instructions.

Typically the method includes, in the processing first system, at least one of:

- a) transferring the instructions to the second processing system; and,
- 15 b) causing the second processing system to access the instructions from a store.

Typically the method includes, in the processing system, receiving the configuration data from at least one of a computer system and a communications network.

Typically the method includes, in the processing system:

- a) determining if a feature selected by a user is available;
- 20 b) if the feature is not available, determining if the user wishes to enable the feature; and,
- c) if the user wishes to enable the feature, causing configuration data to be received.

Typically the method includes, in the processing system:

- a) causing the user to provide a payment to a device provider; and,
- b) receiving the configuration data in response to payment.

25 In a tenth broad form the present invention provides apparatus for configuring a measuring device for measuring the impedance of a subject, the apparatus including a processing system for:

- a) receiving configuration data, the configuration data being indicative of at least one feature;
- b) determining, using the configuration data, instructions representing the at least one feature; and,
- 30 c) causing, at least in part using the instructions, at least one of:
  - i) impedance measurements to be performed; and,

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ii) analysis of impedance measurements.

In an eleventh broad form the present invention provides a method for configuring a measuring device for measuring the impedance of a subject, the method including, in a computer system:

- a) determining configuration data required for a measuring device, the configuration data being indicative of at least one feature; ; and,
- b) causing the configuration data to be received by a processing system in the measuring device, the processing system being responsive to the configuration data to configure the measuring device to allow the at least one feature to be used.

Typically the method includes, in the computer system:

- a) determining a device identifier, the device identifier being associated with the measuring device to be configured; and,
- b) using the device identifier to at least one of:
  - i) transfer the configuration data to the measuring device; and,
  - ii) encrypt the configuration data.

Typically the method includes, in the computer system, determining the configuration data is required in response to at least one of:

- a) payment made by a user of the measuring device; and,
- b) approval of the feature.

Typically the method includes, in the computer system:

- a) determining regulatory approval of the at least one feature in at least one region;
- b) determining at least one measuring device in the at least one region; and,
- c) configuring the at least one measuring device.

In a twelfth broad form the present invention provides apparatus for configuring a measuring device for measuring the impedance of a subject, the method including, in a computer system:

- a) determining configuration data required for a measuring device, the configuration data being indicative of at least one feature; ; and,
- b) causing the configuration data to be received by a processing system in the measuring device, the processing system being responsive to the configuration data to configure the measuring device to allow the at least one feature to be used.

In a thirteenth broad form the present invention provides a method of performing impedance measurements on a subject, wherein the method includes, in a processing system:

- a) causing a first signal to be applied to the subject;

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- b) determining at least one parameter relating to at least one second signal measured across the subject;
- c) comparing the at least one parameter to at least one threshold; and,
- d) depending on the results of the comparison, selectively repeating steps (a) to (d) using a first  
5 signal having an increased magnitude.

Typically the method includes, in the processing system:

- a) determining an animal type of the subject; and,
- b) selecting the threshold in accordance with the animal type.

Typically the threshold is indicative of at least one of:

- 10 a) a minimum second signal magnitude; and,
- b) a minimum signal to noise ratio for the second signal.

Typically the method includes, in the processing system:

- a) determining at least one parameter relating to the at least one first signal;
- b) comparing the at least one parameter to at least one threshold; and,
- 15 c) selectively terminating impedance measurements depending on the results of the comparison.

Typically the threshold is indicative of a maximum first signal magnitude.

In a fourteenth broad form the present invention provides apparatus for performing impedance measurements on a subject, wherein the apparatus includes a processing system for:

- a) causing a first signal to be applied to the subject;
- 20 b) determining at least one parameter relating to at least one second signal measured across the subject;
- c) comparing the at least one parameter to at least one threshold; and,
- d) depending on the results of the comparison, selectively repeating steps (a) to (d) using a first signal having an increased magnitude.

25 Typically the apparatus further includes a variable magnitude current supply.

In another broad form the present invention provides a method of providing an electrode for use in impedance measurement procedures, the method including:

- a) providing on a substrate:
  - i) a number of electrically conductive contact pads; and,
  - 30 ii) a corresponding number of electrically conductive tracks, each track extending from an edge of the substrate to a respective contact pad;

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- b) applying an insulating layer to the substrate, the insulating layer including a number of apertures, and being positioned to thereby overlay the tracks with at least a portion of each pad contact aligned with a respective aperture; and,
- c) providing an electrically conductive medium in the apertures.

5 Typically the electrically conductive medium is formed from a conductive gel.

Typically the conductive gel is silver/silver chloride gel.

Typically the method includes, providing a covering layer on the insulating layer to thereby cover the electrically conductive medium.

Typically the insulating layer has an adhesive surface that releasably engages the covering layer.

10 Typically the substrate is an elongate substrate, and wherein the method includes aligning the pad contacts along the length of the substrate.

Typically the method includes providing the tracks and contact pads using at least one of:

- a) screen printing;
- b) inkjet printing; and,
- 15 c) vapour deposition.

Typically the tracks and contact pads are formed from silver.

Typically the method includes forming the substrate by:

- a) overlaying a plastic polymer with a shielding material; and,
- b) covering the shielding material with an insulating material.

20 In a fifteenth broad form the present invention provides an electrode for use in impedance measurement procedures, the electrode including:

- a) a substrate having provided thereon:
  - i) a number of electrically conductive contact pads; and,
  - 25 ii) a corresponding number of electrically conductive tracks, each track extending from an edge of the substrate to a respective contact pad;
- b) an insulating layer provided on the substrate, the insulating layer including a number of apertures, and being positioned to thereby overlay the tracks with at least a portion of each pad contact aligned with a respective aperture; and,
- c) an electrically conductive medium provided in the apertures.

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In a sixteenth broad form the present invention provides a method for use in diagnosing conditions in a subject, the method including, in a processing system:

- a) determining an encoded value associated with at least one electrode lead; and,
- b) causing at least one impedance measurement to be performed using the encoded value.

5 In a seventeenth broad form the present invention provides a method for use in diagnosing conditions in a subject, the method including, in a processing system:

- a) determining an electrode identifier associated with at least one electrode provided on the subject;
- b) determining, using the electrode identifier, an electrode position indicative of the position of  
10 the at least one electrode on the subject; and,
- c) causing at least one impedance measurement to be performed using the electrode position.

In an eighteenth broad form the present invention provides a method for use in diagnosing conditions in a subject, the method including, in a processing system:

- a) receiving configuration data, the configuration data being indicative of at least one feature;
- 15 b) determining, using the configuration data, instructions representing the at least one feature; and,
- c) causing the measuring device to perform, using the instructions, at least one of:
  - i) impedance measurements; and,
  - ii) analysis of impedance measurements.

20 In a nineteenth broad form the present invention provides a method for use in diagnosing conditions in a subject, the method including, in a processing system:

- a) determining configuration data required for a measuring device, the configuration data being indicative of at least one feature; ; and,
- b) causing the configuration data to be received by a processing system in the measuring device,  
25 the processing system being responsive to the configuration data to configure the measuring device to allow the at least one feature to be used.

In a twentieth broad form the present invention provides a method for use in diagnosing conditions in a subject, the method including, in a processing system:

- a) causing a first signal to be applied to the subject;
- 30 b) determining at least one parameter relating to at least one second signal measured across the subject;
- c) comparing the at least one parameter to at least one threshold; and,

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- d) depending on the results of the comparison, selectively repeating steps (a) to (d) using a first signal having an increased magnitude.

It will be appreciated that the broad forms of the invention may be used individual or in combination, and may be used for diagnosis of the presence, absence or degree of a range of conditions and illnesses, including, but not limited to oedema, pulmonary oedema, lymphodema, body composition, cardiac function, and the like.

### **Brief Description of the Drawings**

An example of the present invention will now be described with reference to the accompanying drawings, in which: -

- 10 Figure 1 is a schematic of an example of impedance determination apparatus;  
Figure 2 is a flowchart of an example of a process for performing impedance determination;  
Figure 3 is a schematic of a second example impedance determination apparatus;  
Figure 4 is a schematic of an example of a current source circuit;  
Figure 5 is a schematic of an example of a buffer circuit for use in voltage sensing;  
15 Figures 6A and 6B is a flowchart of a second example of a process for performing impedance determination;  
Figures 7A and 7B are schematics of an example of an electrode connection;  
Figure 8 is a schematic of a third example of impedance determination apparatus;  
Figure 9 is a schematic of a fourth example of impedance determination apparatus; and,  
20 Figure 10 is a schematic of a fifth example of impedance determination apparatus;  
Figures 11A and 11B are schematic diagrams of a second example of an electrode connection;  
Figures 11C to 11G are schematic diagrams of a third example of an electrode connection;  
Figures 12A to 12F are schematic diagrams of an example of the construction of a band electrode;  
Figures 12G and 12H are schematic diagrams of an example of a connector arrangement for the band  
25 electrode;  
Figure 12I is a schematic diagram of the use of a band electrode;  
Figure 13 is a schematic of a second example of a current source circuit;  
Figure 14 is a flow chart of an example of using the current source circuit of Figure 13;  
Figure 15 is a flow chart of an overview of an example of the process of updating a measuring device;  
30 Figure 16 is a schematic diagram of an example of a system architecture for updating a measuring device;  
Figure 17 is a flow chart of a first example of the process of updating a measuring device;  
Figure 18 is a flow chart of a second example of the process of updating a measuring device; and,



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Figure 19 is a schematic of an example of a housing configuration for impedance determination apparatus.

### **Detailed Description of the Preferred Embodiments**

An example of apparatus suitable for performing an analysis of a subject's bioelectric impedance will now be described with reference to Figure 1.

As shown the apparatus includes a measuring device 1 including a processing system 2 coupled to a signal generator 11 and a sensor 12. In use the signal generator 11 and the sensor 12 are coupled to respective electrodes 13, 14, 15, 16, provided on a subject S, via leads L, as shown. An optional external interface 23 can be used to couple the measuring device 1 to one or more peripheral devices 4, such as an external database or computer system, barcode scanner, or the like.

In use, the processing system 2 is adapted to generate control signals, which causes the signal generator 11 to generate one or more alternating signals, such as voltage or current signals, which can be applied to a subject S, via the electrodes 13, 14. The sensor 12 then determines the voltage across or current through the subject S, using the electrodes 15, 16 and transfers appropriate signals to the processing system 2.

Accordingly, it will be appreciated that the processing system 2 may be any form of processing system which is suitable for generating appropriate control signals and interpreting an indication of the measured signals to thereby determine the subject's bioelectrical impedance, and optionally determine other information such as the cardiac parameters, presence absence or degree of oedema, or the like.

The processing system 2 may therefore be a suitably programmed computer system, such as a laptop, desktop, PDA, smart phone or the like. Alternatively the processing system 2 may be formed from specialised hardware. Similarly, the I/O device may be of any suitable form such as a touch screen, a keypad and display, or the like.

It will be appreciated that the processing system 2, the signal generator 11 and the sensor 12 may be integrated into a common housing and therefore form an integrated device. Alternatively, the processing system 2 may be connected to the signal generator 11 and the sensor 12 via wired or wireless connections. This allows the processing system 2 to be provided remotely to the signal generator 11 and the sensor 12. Thus, the signal generator 11 and the sensor 12 may be provided in a unit near, or worn by the subject S, whilst the processing system 2 is situated remotely to the subject S.

In one example, the outer pair of electrodes 13, 14 are placed on the thoracic and neck region of the subject S. However, this depends on the nature of the analysis being performed. Thus, for example, whilst this electrode arrangement is suitable for cardiac function analysis, in lymphoedema, the electrodes would typically be positioned on the limbs, as required.

- 5    Once the electrodes are positioned, an alternating signal is applied to the subject S. This may be performed either by applying an alternating signal at a plurality of frequencies simultaneously, or by applying a number of alternating signals at different frequencies sequentially. The frequency range of the applied signals may also depend on the analysis being performed.

- 10   In one example, the applied signal is a frequency rich current from a current source clamped, or otherwise limited, so it does not exceed the maximum allowable subject auxiliary current. However, alternatively, voltage signals may be applied, with a current induced in the subject being measured. The signal can either be constant current, impulse function or a constant voltage signal where the current is measured so it does not exceed the maximum allowable subject auxiliary current.

- 15   A potential difference and/or current are measured between an inner pair of electrodes 15, 16. The acquired signal and the measured signal will be a superposition of potentials generated by the human body, such as the ECG, and potentials generated by the applied current.

- 20   Optionally the distance between the inner pair of electrodes may be measured and recorded. Similarly, other parameters relating to the subject may be recorded, such as the height, weight, age, sex, health status, any interventions and the date and time on which they occurred. Other information, such as current medication, may also be recorded.

To assist accurate measurement of the impedance, buffer circuits may be placed in connectors that are used to connect the voltage sensing electrodes 15, 16 to the leads L. This ensures accurate sensing of the voltage response of the subject S, and in particular helps eliminate contributions to the measured voltage due to the response of the leads L, and reduce signal loss.

- 25   This in turn greatly reduces artefacts caused by movement of the leads L, which is particularly important during dialysis as sessions usually last for several hours and the subject will move around and change positions during this time.

- 30   A further option is for the voltage to be measured differentially, meaning that the sensor used to measure the potential at each electrode 15, 16 only needs to measure half of the potential as compared to a single ended system.

The current measurement system may also have buffers placed in the connectors between the electrodes 13, 14 and the leads L. In one example, current can also be driven or sourced through the subject S symmetrically, which again greatly reduced the parasitic capacitances by halving the common-mode current. Another particular advantage of using a symmetrical system is that the micro-electronics built into the connectors for each electrode 13, 14 also removes parasitic capacitances that arise when the subject S, and hence the leads L move.

The acquired signal is demodulated to obtain the impedance of the system at the applied frequencies. One suitable method for demodulation of superposed frequencies is to use a Fast Fourier Transform (FFT) algorithm to transform the time domain data to the frequency domain. This is typically used when the applied current signal is a superposition of applied frequencies. Another technique not requiring windowing of the measured signal is a sliding window FFT.

In the event that the applied current signals are formed from a sweep of different frequencies, then it is more typical to use a processing technique such as multiplying the measured signal with a reference sine wave and cosine wave derived from the signal generator, or with measured sine and cosine waves, and integrating over a whole number of cycles. This process rejects any harmonic responses and significantly reduces random noise.

Other suitable digital and analog demodulation techniques will be known to persons skilled in the field.

Impedance or admittance measurements are determined from the signals at each frequency by comparing the recorded voltage and current signal. The demodulation algorithm will produce an amplitude and phase signal at each frequency.

An example of the operation of the apparatus for performing impedance analysis will now be described with reference to Figure 2.

At step 100, the processing system 2 operates to generate control signals which are provided to the signal generator 11 at step 110, thereby causing the signal generator to apply an alternating current signal to the subject S, at step 120. Typically the signal is applied at each of a number of frequencies  $f_i$  to allow multiple frequency analysis to be performed.

At step 130 the sensor 12 senses voltage signals across the subject S. At step 140 the measuring device, operates to digitise and sample the voltage and current signals across the subject S, allowing these to be used to determine instantaneous impedance values for the subject S at step 150.

A specific example of the apparatus will now be described in more detail with respect to Figure 3.

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In this example, the processing system 2 includes a first processing system 10 having a processor 20, a memory 21, an input/output (I/O) device 22, and an external interface 23, coupled together via a bus 24. The processing system 2 also includes a second processing system 17, in the form of a processing module. A controller 19, such as a micrologic controller, may also be provided to control activation  
5 of the first and second processing systems 10, 17.

In use, the first processing system 10 controls the operation of the second processing system 17 to allow different impedance measurement procedures to be implemented, whilst the second processing system 17 performs specific processing tasks, to thereby reduce processing requirements on the first processing system 10.

10 Thus, the generation of the control signals, as well as the processing to determine instantaneous impedance values is performed by the second processing system 17, which may therefore be formed from custom hardware, or the like. In one particular example, the second processing system 17 is formed from a Field Programmable Gate Array (FPGA), although any suitable processing module, such as a magnetologic module, may be used.

15 The operation of the first and second processing systems 10, 17, and the controller 19 is typically controlled using one or more sets of appropriate instructions. These could be in any suitable form, and may therefore include, software, firmware, embedded systems, or the like.

The controller 19 typically operates to detect activation of the measuring device through the use of an on/off switch (not shown). Once the controller detects device activation, the controller 19 executes  
20 predefined instructions, which in turn causes activation of the first and second processing systems 10, 17, including controlling the supply of power to the processing systems as required.

The first processing system 10 can then operate to control the instructions, such as the firmware, implemented by the second processing system 17, which in turn alters the operation of the second processing system 17. Additionally, the first processing system 10 can operate to analyse impedance  
25 determined by the second processing system 17, to allow biological parameters to be determined. Accordingly, the first processing system 10 may be formed from custom hardware or the like, executing appropriate applications software to allow the processes described in more detail below to be implemented.

It will be appreciated that this division of processing between the first processing system 10, and the  
30 second processing system 17, is not essential, but there are a number of benefits that will become apparent from the remaining description.

In this example, the second processing system 17 includes a PCI bridge 31 coupled to programmable module 36 and a bus 35, as shown. The bus 35 is in turn coupled to processing modules 32, 33, 34, which interface with ADCs (Analogue to Digital Converters) 37, 38, and a DAC (Digital to Analogue Converter) 39, respectively.

5 The programmable module 36 is formed from programmable hardware, the operation of which is controlled using the instructions, which are typically downloaded from the first processing system 10. The firmware that specifies the configuration of hardware 36 may reside in flash memory (not shown), in the memory 21, or may be downloaded from an external source via the external interface 23.

10 Alternatively, the instructions may be stored within inbuilt memory on the second processing system 17. In this example, the first processing system 10 typically selects firmware for implementation, before causing this to be implemented by the second processing system 17. This may be achieved to allow selective activation of functions encoded within the firmware, and can be performed for example using configuration data, such as a configuration file, or instructions representing  
15 applications software or firmware, or the like, as will be described in more detail below.

In either case, this allows the first processing system 10 to be used to control operation of the second processing system 17 to allow predetermined current sequences to be applied to the subject S. Thus, for example, different firmware would be utilised if the current signal is to be used to analyse the impedance at a number of frequencies simultaneously, for example, by using a current signal formed  
20 from a number of superposed frequencies, as compared to the use of current signals applied at different frequencies sequentially.

An example of a specific form of signal generator 11 in the form of a current source circuit, is shown in Figure 4.

25 As shown the current source includes three fixed or variable gain differential amplifiers  $A_1$ ,  $A_2$ ,  $A_3$  and three op-amps  $A_4$ ,  $A_5$ ,  $A_6$ , a number of resistors  $R_1$ , ...  $R_{17}$  and capacitors  $C_1$ , ...  $C_4$ , interconnected as shown. The current source also includes leads 41, 42 (corresponding to the leads L in Figure 1) which connect the current source to the electrodes 13, 14 and a switch SW for shorting the leads 41, 42 as will be described in more detail below.

30 Connections 45, 46 can also be provided for allowing the current applied to the subject S to be determined. Typically this is achieved using the connection 46. However, the connection 45 may also be used as shown in dotted lines to allow signal losses within the leads and other circuitry to be taken into account.

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In general the leads used are co-axial cables with a non-braided shield and a multi strand core with a polystyrene dielectric. This provides good conductive and noise properties as well as being sufficiently flexible to avoid issues with connections from the measuring device 1 to the subject S. In this instance, resistors  $R_{12}$ ,  $R_{13}$  decouple the outputs of the amplifiers  $A_5$ ,  $A_6$  from the capacitances associated with cable.

In use, the current source circuit receives current control signals  $I^+$ ,  $I^-$  from the DAC 39, with these signals being filtered and amplified, to thereby form current signals that can be applied to the subject S via the electrodes 13, 14.

In use, when the amplifiers  $A_1$ , ...,  $A_6$  are initially activated, this can lead to a minor, and within safety limits, transient current surge. As the current is applied to the subject, this can result in the generation of a residual field across the subject S. To avoid this field effecting the readings, the switch SW is generally activated prior to measurements being taken, to short the current circuit, and thereby discharge any residual field.

Once the measurement is commenced, an indication of the current applied to the subject can be obtained via either one of the connections 45, 46, that are connected to the ADC 38, as shown by the dotted lines.

This allows the current supplied across the subject to be accurately determined. In particular, by using the actual applied current, as opposed to estimating the current applied on the basis of the control signals  $I^+$ ,  $I^-$ , this takes into account non-ideal behaviour of the components in the current source, and can also take into account the effects of the leads 41, 42, on the applied current.

In one example, the amplifier  $A_3$  and associated components may be provided on a housing coupled to the electrodes 12, 13, allowing more accurate sensing of the current applied to the subject. In particular, this avoids measuring of cable effects, such as signal loss in the leads L.

The above is an example of a non-symmetric current source and it will be appreciated that symmetric current sources may alternatively be used.

An example of the buffer used for the voltage electrodes is shown in Figure 5. In this example, each electrode 15, 16, will be coupled to a buffer circuit 50A, 50B.

In this example, each buffer 50A, 50B includes amplifiers  $A_{10}$ ,  $A_{11}$ , and a number of resistors  $R_{21}$ , ...,  $R_{26}$ , interconnected as shown. In use, each buffer 50A, 50B, is connected a respective electrode 15, 16 via connections 51, 52. The buffers 50A, 50B are also connected via leads 53, 54 to a differential amplifier 55, acting as the signal sensor 12, which is in turn coupled to the ADC 37. It will therefore

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be appreciated that a respective buffer circuit 50A, 50B is connected to each of the electrodes 15, 16, and then to a differential amplifier, allowing the potential difference across the subject to be determined.

5 In one example, the leads 53, 54 correspond to the leads L shown in Figure 1, allowing the buffer circuits 50A, 50B to be provided in connector housing coupled to the electrodes 15, 16, as will be described in more detail below.

10 In use, the amplifier  $A_{10}$  amplifies the detected signals and drives the core of the cable 53, whilst the amplifier  $A_{11}$  amplifies the detected signal and drives the shield of the cables 51, 53. Resistors  $R_{26}$  and  $R_{25}$  decouple the amplifier outputs from the capacitances associated with cable, although the need for these depends on the amplifier selected.

Again, this allows multi-core shielded cables to be used to establish the connections to the voltage electrodes 15, 16.

An example of operation of the apparatus will now be described with reference to Figures 6A to 6C.

15 At step 200 an operator selects an impedance measurement type using the first processing system 10. This may be achieved in a number of ways and will typically involve having the first processing system 10 store a number of different profiles, each of which corresponds to a respective impedance measurement protocol.

20 Thus, for example, when performing cardiac function determination, it will be typical to use a different applied current sequence and a different impedance analysis, as compared to performing lymphoedema measurements, body composition, pulmonary oedema, or the like. The profile will typically be stored in the memory 21, or alternatively may be downloaded from flash memory (not shown), or via the external interface 23.

25 Once an appropriate measurement type has been selected by the operator, this will cause the first processing system 10 to load desired code module firmware into the programmable module 36 of the second processing system 17 at step 210, or cause embedded firmware to be activated. The type of code module used will depend on the preferred implementation, and in one example this is formed from a wishbone code module, although this is not essential.

30 At step 220, the second processing system 17 is used to generate a sequence of digital control signals, which are transferred to the DAC 39 at step 230. This is typically achieved using the processing module 34, by having the module generate a predetermined sequence of signals based on the selected

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impedance measurement profile. This can therefore be achieved by having the second processing system 17 program the processing module 34 to cause the module to generate the required signals.

The DAC 39 converts the digital control signals into analogue control signals  $I^+$ ,  $I^-$  which are then applied to the current source 11 at step 240.

- 5 As described above, the current source circuit shown in Figure 4 operates to amplify and filter the electrical control signals  $I^+$ ,  $I^-$  at step 250, applying the resulting current signals to the electrodes 13, 14 at step 260.

During this process, and as mentioned above, the current circuit through the subject can optionally be shorted at step 270, using the switch SW, to thereby discharge any residual field in the subject S, prior  
10 to readings being made.

At step 280, the measurement procedure commences, with the voltage across the subject being sensed from the electrodes 15, 16. In this regard, the voltage across the electrodes is filtered and amplified using the buffer circuit shown in Figure 5 at step 290, with the resultant analogue voltage signals V being supplied to the ADC 37 and digitised at step 300. Simultaneously, at step 310 the current  
15 applied to the subject S is detected via one of the connections 45, 46, with the analogue current signals I being digitised using the ADC 38 at step 320.

The digitised voltage and current signals V, I are received by the processing modules 32, 33 at step 330, with these being used to performed preliminary processing of the signals at step 340.

The processing performed will again depend on the impedance measurement profile, and the  
20 consequent configuration of the processing modules 32, 33. This can include for example, processing the voltage signals V to extract ECG signals. The signals will also typically be filtered to ensure that only signals at the applied frequencies  $f_i$  are used in impedance determination. This helps reduce the effects of noise, as well as reducing the amount of processing required.

At step 350 the second processing system 17 uses the processing signals to determine voltage and  
25 current signals at each applied frequency  $f_i$ , with these being used at step 360 to determine instantaneous impedance values at each applied frequency  $f_i$ .

The ADCs 37, 38 and the processing modules 32, 33 are typically adapted to perform sampling and processing of the voltage and current signals V, I in parallel so that the voltage induced at the corresponding applied current are analysed simultaneously. This reduces processing requirements by  
30 avoiding the need to determine which voltage signals were measured at which applied frequency. This is achieved by having the processing modules 32, 33 sample the digitised signals received from



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the ADCs 37, 38, using a common clock signal generated by the processing module 36, which thereby ensures synchronisation of the signal sampling.

Once the instantaneous impedance values have been derived, these can undergo further processing in either the first processing system 10, or the second processing system 17, at step 370. The processing of the instantaneous impedance signals will be performed in a number of different manners depending on the type of analysis to be used and this in turn will depend on the selection made by the operator at step 200.

Accordingly, it will be appreciated by persons skilled in the art that a range of different current sequences can be applied to the subject by making an appropriate measurement type selection. Once this has been performed, the FPGA operates to generate a sequence of appropriate control signals  $I^+$ ,  $I^-$ , which are applied to the subject S using the current supply circuit shown in Figure 4. The voltage induced across the subject is then sensed using the buffer circuit shown in Figure 5, allowing the impedance values to be determined and analysed by the second processing system 17.

Using the second processing system 17 allows the majority of processing to be performed using custom configured hardware. This has a number of benefits.

Firstly, the use of an second processing system 17 allows the custom hardware configuration to be adapted through the use of appropriate firmware. This in turn allows a single measuring device to be used to perform a range of different types of analysis.

Secondly, this vastly reduces the processing requirements on the first processing system 10. This in turn allows the first processing system 10 to be implemented using relatively straightforward hardware, whilst still allowing the measuring device to perform sufficient analysis to provide interpretation of the impedance. This can include for example generating a "Wessel" plot, using the impedance values to determine parameters relating to cardiac function, as well as determining the presence or absence of lymphoedema.

Thirdly, this allows the measuring device 1 to be updated. Thus for example, if an improved analysis algorithms is created, or an improved current sequence determined for a specific impedance measurement type, the measuring device can be updated by downloading new firmware via flash memory (not shown) or the external interface 23.

It will be appreciated that in the above examples, the processing is performed partially by the second processing system 17, and partially by the first processing system 10. However, it is also possible for processing to be performed by a single element, such as an FPGA, or a more generalised processing system.

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As the FPGA is a custom processing system, it tends to be more efficient in operation than a more generic processing system. As a result, if an FPGA alone is used, it is generally possible to use a reduced overall amount of processing, allowing for a reduction in power consumption and size. However, the degree of flexibility, and in particular, the range of processing and analysis of the impedance which can be performed is limited.

Conversely, if only a generic processing system is used, the flexibility is enhanced at the expense of a decrease in efficiency, and a consequent increase in size and power consumption.

Accordingly, the above described example strikes a balance, providing custom processing in the form of an FPGA to perform partial processing. This can allow for example, the impedance values to be determined. Subsequent analysis, which generally requires a greater degree of flexibility can then be implemented with the generic processing system.

A further disadvantage of utilising an FPGA alone is that it complicates the process of updating the processing, for example, if improved processing algorithms are implemented.

#### Electrode Connections

An example of an electrode connection apparatus is shown in Figures 7A and 7B.

In particular, in this example, the connector includes circuitry provided on a substrate such as a PCB (Printed Circuit Board) 61, which is in turn mounted in a housing 60 as shown. The housing 60 includes an arm 62 which is urged toward a contact 63 provided on the substrate 61. The substrate 61 is then coupled to a respective one of the ADCs 37, 38 or the DAC 39, via appropriate leads shown generally at L, such as the leads 41, 42, 53, 54.

In use, the connector couples to a conductive electrode substrate 65, such as a plastic coated in silver, and which in turn has a conductive gel 64, such as silver/silver chloride gel thereon. The arm 62 urges the conductive electrode substrate 65 against the contact 63, thereby electrically coupling the conductive gel 64 to the circuit provided on the substrate 61.

This ensures good electrical contact between the measuring device 1 and the subject S, as well as reducing the need for leads between the electrodes 13, 14 and the input of the voltage buffers, removing the requirement for additional leads, which represents an expense, as well as a source of noise within the apparatus.

In this example, the edges and corners of the housing 60, the arm 62 and the substrate 65 are curved.

This is to reduce the chance of a subject being injured when the connector is attached to the electrode.

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This is of particular importance when using the electrodes on lymphodema sufferers, when even a small nip of the skin can cause severe complications.

To further enhance the useability of the housing, the housing may be formed from a material that has a low coefficient of friction and/or is spongy or resilient. Again, these properties help reduce the likelihood of the subject being injured when the housing is coupled to the electrode.

#### Electrical Isolation

A further development of the apparatus will now be described with reference to Figure 8.

In this example, the second processing system 17 is formed from two respective FPGA portions 17A, 17B. The two FPGA portions 17A, 17B are interconnected via an electrically isolated connection shown generally by the dotted line 17C. The electrically isolated connection could be achieved for example using an inductive loop connections, wireless links or the like.

This split in the FPGA can be used to ensure that the measuring device 1 is electrically isolated from the subject S. This is important for example when taking readings with a high degree of accuracy.

In this example, the second processing system 17 will typically be implemented such that the operation of the second FPGA portion 17B is substantially identical for all measurement types. As a result, there is no requirement to upload firmware into the second FPGA portion 17B to allow different types of impedance analysis.

In contrast to this, the first FPGA portion 17A will typically implement firmware depending on the impedance measurement type in a manner substantially as described above.

It will therefore be appreciated that this provides a mechanism by which the measuring device 1 is electrically isolated from the subject, whilst still allowing the benefits of use of the second processing system 17 to be achieved.

Alternatively, equivalent electrical isolation can be obtained by providing a single FPGA electrically isolated from the first processing system 10.

In this example, the second FPGA portion 17B can be provided into a subject unit, shown generally at 2, which includes the lead connections.

This allows a single measuring device 1 to communicate with a number of different subject units, each of which is associated with a respective subject S. This allows the measuring device 1 to provide centralised monitoring of a number of different subjects via way of a number of subject units

2. This in turn allows a number of subjects to be analysed in sequence without having to reconnect each subject S each time an analysis is to be performed.

### Lead Calibration

To assist in interpreting the impedance measurements, it is useful to take into account electrical properties of the connecting leads and associated circuitry.

To achieve this, the leads and corresponding connections can be encoded with calibration information. This can include, for example, using specific values for respective ones of the resistors in the current source, or buffer circuits shown in Figures 4 and 5. Thus for example, the value of the resistors  $R_{12}$ ,  $R_{13}$ ,  $R_{26}$  can be selected based on the properties of the corresponding leads.

In this instance, when the leads are connected to the measuring device 1, via the corresponding ADCs 37, 38, the processing modules 32, 33 can be to interrogate the circuitry using appropriate polling signals to thereby determine the value of corresponding resistor. Once this value has been determined, the second processing system 17 can use this to modify the algorithm used for processing the voltage and current signals to thereby ensure correct impedance values are determined.

In addition to this, the resistance value can also act as a lead identifier, to allow the measuring device to identify the leads and ensure that only genuine authorised leads are utilised. Thus, for example, if the determined resistance value does not correspond to a predetermined value this can be used to indicate that non-genuine leads are being used. In this instance, as the lead quality can have an effect on the accuracy of the resultant impedance analysis, it may be desirable to either generate an error message or warning indicating that incorrect leads are in use. Alternatively, the second processing system 17 can be adapted to halt processing of the measured current and voltage signals. This allows the system to ensure that only genuine leads are utilised.

This can further be enhanced by the utilisation of a unique identifier associated with each lead connection circuit. In this instance, a unique identifier can be encoded within an IC provided as part of the current source or voltage buffer circuits. In this instance, the measuring device 1 interrogates the unique identifier and compared to unique identifiers stored either in local memory, or in a central database, allowing genuine leads to be identified.

This process can also be used to monitor the number of times a lead has been used. In this instance, each time a lead is used, data reflecting lead usage is recorded. This allows the leads to have a predesignated use quota life span, and once the number of times the lead is used reaches the quota, further measurements using the leads can be prevented. Similarly, a temporal limitation can be

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applied by providing an expiry date associated with the lead. This can be based on the date the lead is created, or first used depending on the preferred implementation.

It will be appreciated that when recording lead usage, issues may arise if this is recorded locally. In particular, this could allow a lead to be re-used with a different measuring device. To avoid this, the leads can be configured with a ID which is set by the measuring device on first use. This can be used to limit usage of the leads to a single measuring device.

This can be used to ensure that the leads are correctly replaced in accordance with a predetermined lifespan thereby helping to ensure accuracy of measure impedance values.

#### Multiple channel

10 A further variation to the apparatus is shown in Figure 9.

In this example, the apparatus is adapted to provide multiple channel functionality allowing different body segments to undergo impedance analysis substantially simultaneously. In this instance, this is achieved by providing first and second processing modules 32A, 32B, 33A, 33B, 34A, 34B, first and second ADCs and DACs 37A, 37B, 38A, 38B, 39A, 39B as well as first and second voltage and current circuits 11A, 11B, 12A, 12B, in parallel, as shown.

Thus, the measuring device 1 includes two separate impedance measuring channels indicated by the use of reference numerals A, B. In this instance, this allows electrodes to be attached to body segments, such as different limbs, with measurements being taken from each segment substantially simultaneously.

20 As an alternative to the above described arrangement, multiple channels could alternatively be implemented by utilising two separate second processing modules 17, each one being associated with a respective channel. Alternatively, the signals applied to each channel could be applied via multiplexers positioned between the ADCs 37, 38 and the DAC 39 and the electrodes.

It will be appreciated that whilst two channels are shown in the above example, this is for clarity only, and any number of channels may be provided.

#### Switching Arrangement

Figure 10 shows an example of an impedance measuring apparatus including a switching arrangement. In this example, the measuring device 1 includes a switching device 18, such as a multiplexer, for connecting the signal generator 11 and the sensor 12 to the leads L. This allows the

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measuring device 1 to control which of the leads L are connected to the signal generator 11 and the sensor 12.

In this example, a single set of leads and connections is shown. This arrangement can be used in a number of ways. For example, by identifying the electrodes 13, 14, 15, 16 to which the measuring device 1 is connected, this can be used to control to which of the leads L signals are applied, and via which leads signals can be measured. This can be achieved either by having the user provide an appropriate indication via the input device 22, or by having the measuring device 1 automatically detect electrode identifiers, as will be described in more detail below.

Alternatively, however the arrangement may be used with multiple leads and electrodes to provide multi-channel functionality as described above.

#### Electrode Configuration

An example of an alternative electrode configuration will now be described with reference to Figures 11A and 11B.

In this example, the electrode connector is formed from a housing 1100 having two arms 1101, 1102 arranged to engage with an electrode substrate 1105 to thereby couple the housing 1100 to the substrate 1105. A contact 1103 mounted on an underside of the arm 1102, is urged into contact and/or engagement with an electrode contact 1104 mounted on a surface of the electrode substrate 1105. The electrode also includes a conductive gel 1106, such as a silver/silver chloride gel, electrically connected to the contact 1104. This can be achieved, either by using a conductive track, such as a silver track, or by using a conductive substrate such as plastic coated in silver.

This allows the lead L to be electrically connected to the conductive gel 1106, allowing current to be applied to and/or a voltage measured from the subject S to which they are attached. It will be appreciated that in this example the above described housing 1100 may also contain the buffer circuit 50, or all or part of the current source circuit shown in Figure 4, in a manner similar to that described above with respect to Figure 7.

Alternatively more complex interconnections may be provided to allow the measuring device 1 to identify specific electrodes, or electrode types.

This can be used by the measuring device 1 to control the measurement procedure. For example, detection of an electrode type by the processing system 2 may be used to control the measurements and calculation of different impedance parameters, for example to determine indicators for use in detecting oedema, monitoring cardiac function, or the like.

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Similarly, electrodes can be provided with visual markings indicative of the position on the subject to which the electrode should be attached. For example a picture of a left hand can be shown if the electrode pad is to be attached to a subject's left hand. In this instance, identification of the electrodes can be used to allow the measuring device 1 to determine where on the subject the electrode is attached and hence control the application and measurement of signals accordingly.

An example of this will now be described with reference to Figures 11C to 11G. In this example the contact 1103 is formed from a contact substrate 1120, such as a PCB, having a number of connector elements 1121, 1122, 1123, 1124, formed from conductive contact pads, typically made of silver or the like. The connector elements are connected to the lead L via respective electrically conductive tracks 1126, typically formed from silver, and provided on the contact substrate 1120. The lead L includes a number of individual wires, each electrically coupled to a respective one of the connector elements 1121, 1122, 1123, 1124.

In this example the electrode contact 1104 on the electrode substrate 1105 typically includes an electrode contact substrate 1130, including electrode connector elements 1131, 1132, 1133, 1134, typically formed from silver contact pads or the like. The electrode connector elements 1131,... 1134 are positioned so that, in use, when the electrode connector 1100 is attached to an electrode, the connector elements 1121...1124 contact the electrode connector elements 1131,... 1134 to allow transfer of electrical signals with the measuring device 1.

In the examples, of Figures 11D to 11G, the connector element 1131 is connected to the conductive gel 1106, via an electrically conductive track 1136, typically a silver track that extends to the underside of the electrode substrate 1105. This can be used by the measuring device 1 to apply a current to, or measure a voltage across the subject S.

Additionally, selective ones of the connector elements 1132, 1133, 1134 are also interconnected in four different arrangements by respective connectors 1136A, 1136B, 1136C, 1136D. This allows the measuring device 1 to detect which of the electrode contacts 1122, 1123, 1124 are interconnected, by virtue of the connectors, 1136A, 1136B, 1136C, 1136D, with the four different combinations allowing the four different electrodes to be identified.

Accordingly, the arrangement of Figures 11D to 11G can be used to provide four different electrodes, used as for example, two current supply 13, 14 and two voltage measuring electrodes 15, 16.

In use, the measuring device 1 operates by having the second processing system 17 cause signals to be applied to appropriate wires within each of the leads L, allowing the conductivity between the connecting elements 1122, 1123, 1124, to be measured. This information is then used by the second

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processing system 17 to determine which leads L are connected to which of the electrodes 13, 14, 15, 16. This allows the first processing system 10 or the second processing system 17 to control the multiplexer 18 in the example of Figure 10, to correctly connect the electrodes 13, 14, 15, 16 to the signal generator 11, or the signal sensor 12.

5 In this example, the individual applying the electrode pads to the subject can simply position the electrodes 13, 14, 15, 16 on the subject in the position indicated by visual markings provided thereon. Leads may then be connected to each of the electrodes allowing the measuring device 1 to automatically determine to which electrode 13, 14, 15, 16 each lead L connected and then apply current signals and measure voltage signals appropriately. This avoids the complexity of ensuring the  
10 correct electrode pads are connected via the correct leads L.

It will be appreciated that the above described process allows electrode identification simply by applying currents to the electrode connector. However, other suitable identification techniques can be used, such as through the use of optical encoding. This could be achieved for example, by providing a visual marker, or a number of suitably arranged physical markers on the electrode connector 1104,  
15 or electrode substrate 1105. These could then be detected using an optical sensor mounted on the connector 1100, as will be appreciated by persons skilled in the art.

Alternatively, the identifier for the electrodes may be identified by an encoded value, represented by, for example, the value of a component in the electrode, such as a resistor or capacitor. It will therefore be appreciated that this can be achieved in a manner similar to that described above with  
20 respect to lead calibration.

An example of an alternative electrode configuration will now be described with reference to Figures 12A to 12F. In this particular example the electrode is a band electrode 1200, which includes a number of separate electrodes. In this example the electrode is formed from an elongate substrate 1210 such as a plastic polymer coated with shielding material and an overlaying insulating material.

25 A number of electrically conductive tracks 1220 are provided on the substrate extending from an end of the substrate 1211 to respective conductive contact pads 1230, spaced apart along the length of the substrate in sequence. This allows a connector similar to the connectors described above, but with corresponding connections, to be electrically coupled to the tracks 1220.

The tracks 1220 and the contact pads 1230 may be provided on the substrate 1210 in any one of a  
30 number of manners, including for example, screen printing, inkjet printing, vapour deposition, or the like, and are typically formed from silver or another similar material. It will be appreciated however that the tracks and contact pads should be formed from similar materials to prevent signal drift.



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Following the application of the contact pads 1230 and the tracks 1220, an insulating layer 1240 is provided having a number of apertures 1250 aligned with the electrode contact pads 1230. The insulating layer is typically formed from a plastic polymer coated with shielding material and an overlaying insulating material.

- 5 To ensure adequate conduction between the contact pads 1230, and the subject S, it is typical to apply a conductive gel 1260 to the contact pads 1230. It will be appreciated that in this instance gel can be provided into each of the apertures 1250 as shown. .

A removable covering 1270 is then applied to the electrode, to maintain the electrode's sterility and/or moisture level in the gel. This may be in the form of a peel off strip or the like which when removed  
10 exposes the conductive gel 1260, allowing the electrode to be attached to the subject S.

In order to ensure signal quality, it is typical for each of the tracks 1220 to comprise a shield track 1221, and a signal track 1222, as shown. This allows the shield on the leads L, such as the leads 41, 42, 51 to be connected to the shield track 1221, with the lead core being coupled to the signal track 1222. This allows shielding to be provided on the electrode, to help reduce interference between  
15 applied and measured signals.

This provides a fast straight-forward and cheap method of producing band electrodes. It will be appreciated that similar screen printing techniques may be utilised in the electrode arrangements shown in Figures 7A and 7B, and 11A-11G.

The band electrode may be utilised together with a magnetic connector as will now be described with  
20 respect to Figures 12G and 12H. In this example, the band electrode 1200 includes two magnets 1201A, 1201B positioned at the end 1211 of the substrate 1210. The connector, is formed from a connector substrate 1280 having magnets 1281A, 1281B provided therein. Connecting elements 1282 are also provided, and these would in turn be connected to appropriate leads L.

The magnets 1201A, 1281A; 1201B (not shown for clarity), 1281B can be arranged to align and  
25 magnetically couple, to urge the connector substrate 1280 and the band electrode 1200 together. Correct alignment of the poles of the magnets 1201A, 1281A; 1201B, 1281B can also be used to ensure both the correct positioning and orientation of the connector substrate 1280 and band electrode, which can ensure correct alignment of the connecting elements 1282, with corresponding ones of the tracks 1220, on the band electrode 1200.

30 It will be appreciated that this can be used to ensure correct connection with the electrode, and that a similar magnetic alignment technique may be used in the connectors previously described.

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In use, the band electrode may be attached to the subject's torso, as shown in Figure 12I. The electrode will typically include an adhesive surface, allowing it to stick to the subject. However, a strap 1280 may also be used, to help retain the electrode 1200 in position. This provides an electrode that is easy to attach and position on the subject, and yet can be worn for an extended period if necessary. The band electrode 1200 may also be positioned on the subject at other locations, such as on the side of the subject's torso, or laterally above the naval, as shown.

The band electrode 1200 provides sufficient electrodes to allow cardiac function to be monitored. In the above example, the band electrode includes six electrodes, however any suitable number may be used, although typically at least four electrodes are required.

#### 10 Variable Current

A further feature that can be implemented in the above measuring device is the provision of a signal generator 11 capable of generating a variable strength signal, such as a variable current. This may be used to allow the measuring device 1 to be utilised with different animals, detect problems with electrical connections, or to overcome noise problems.

15 In order to achieve this, the current source circuit shown in Figure 4 is modified as shown in Figure 13. In this example, the resistor  $R_{10}$  in the current source circuit of Figure 4 is replaced with a variable resistor  $VR_{10}$ . Alteration of the resistance of the resistor  $VR_{10}$  will result in a corresponding change in the magnitude of the current applied to the subject S.

To reduce noise and interference between the current source circuit and the control, which is typically achieved using the second processing module 17, it is typical to electrically isolate the variable resistor 17 from the control system. Accordingly in one example, the variable resistor  $VR_{10}$  is formed from a light dependent resistor. In this example, an light emitting diode (LED) or other illumination source can be provided, as shown at  $L_1$ . The LED  $L_1$  can be coupled to a variable power supply P of any suitable form. In use, the power supply P, is controlled by the second processing module 17, thereby controlling the intensity of light generated by the LED  $L_1$ , which in turn allows the resistance  $VR_{10}$ , and hence the applied current, to be varied.

In order to operate the measuring device 1, the first processing system 10 and the second processing system 17 typically implement the process described in Figure 14. In this example, at step 1400 the user selects a measurement or an animal type utilising the input/output device 22.

30 At step 1410 the first processing system 10 and the second processing system 17 interact to determine one or more threshold values based on the selected measurement or animal type. This may be achieved in any one of a number of ways, such as by having the first processing system 10 retrieve

threshold values from the memory 21 and transfer these to the second processing system 17, although any suitable mechanism may be used. In general, multiple thresholds may be used to specify different operating characteristics, for signal parameters such as a maximum current that can be applied to the subject S, the minimum voltage required to determine an impedance measurement, a minimum signal to noise ratio, or the like.

At step 1420 the second processing system 17 will activate the signal generator 11 causing a signal to be applied to the subject S. At step 1430 the response signal at the electrodes 15,16 is measured using the sensor 12 with signals indicative of the signal being returned to the second processing system 17 at step 1430.

At step 1440 the second processing system 17 compares the at least one parameter of the measured signal to a threshold to determine if the measured signal is acceptable at step 1450. This may involve for example determining if the signal to noise levels within the measured voltage signal are above the minimum threshold, or involve to determine if the signal strength is above a minimum value.

If the signal is acceptable, impedance measurements can be performed at step 1460. If not, at step 1470 the second processing system 17 determines whether the applied signal has reached a maximum allowable. If this has occurred, the process ends at step 1490. However, if the maximum signal has not yet been reached, the second processing system 17 will operate to increase the magnitude of the current applied to the subject S at step 1480 before returning to step 1430 to determine a new measured signal.

Accordingly, this allows the current or voltage applied to the subject S to be gradually increased until a suitable signal can be measured to allow impedance values to be determined, or until either a maximum current or voltage value for the subject is reached.

It will be appreciated that the thresholds selected, and the initial current applied to the subject S in step 1420 will typically be selected depending on the nature of the subject. Thus, for example, if the subject is a human it is typical to utilise a lower magnitude current than if the subject is a animal such as a mouse or the like.

#### Device Updates

An example of a process for updating the measuring device will now be described with reference to Figure 15.

In one example, at step 1500 the process involves determining a measuring device 1 is to be configured with an upgrade, or the like, before configuration data is created at step 1510. At step

1520 the configuration data is typically uploaded to the device before the device is activated at 1530. At 1540 when the device commences operation the processing system 2 uses the configuration data to selectively activate features, either for example by controlling the upload of instructions, or by selectively activating instructions embedded within the processing system 2 or the controller 19.

5 This can be achieved in one of two ways. For example, the configuration data could consist of instructions, such as a software or firmware, which when implemented by the processing system 2 causes the feature to be implemented. Thus, for example, this process may be utilised to update the operation of the firmware provided in the second processing system 17, the processing system 10 or the controller 19 to allow additional functionality, improved measuring algorithms, or the like, to be implemented.

Alternatively, the configuration data could be in the form of a list of features, with this being used by the processing system 2 to access instructions already stored on the measuring device 1. Utilisation of configuration data in this manner, allows the measuring device to be loaded with a number of as yet additional features, but non-operational features, when the device is sold. In this example, by 15 updating the configuration data provided on the measuring device 1, this allows these further features to be implemented without requiring return of the measuring device 1 for modification.

This is particularly useful in the medical industry as it allows additional features to be implemented when the feature receives approval for use. Thus, for example, techniques may be available for measuring or detecting lymphoedema in a predetermined way, such as through the use of a particular 20 analysis of measured voltage signals or the like. In this instance when a device is sold, approval may not yet have been obtained from an administering body such as the Therapeutic Goods Administration, or the like. Accordingly, the feature is disabled by appropriate use of a configuration data. When the measurement technique subsequently gains approval, the configuration data can be modified by uploading a new updated configuration data to the measuring device, allowing the feature 25 to be implemented.

It will be appreciated that these techniques may be used to implement any one of a number of different features, such as different measuring techniques, analysis algorithms, reports on results of measured impedance parameters, or the like.

An example of a suitable system for providing updates will now be described with respect to Figure 30 16. In this example, a base station 1600 is coupled to a number of measuring devices 1, and a number of end stations 1603 via a communications network 1602, such as the Internet, and/or via communications networks 1604, such as local area networks (LANs), or wide area networks (WANs). The end stations are in turn coupled to measuring devices 1, as shown.

In use, the base station 1600 includes a processing system 1610, coupled to a database 1611. The base station 1600 operates to determine when updates are required, select the devices to which updates are applied, generate the configuration data and provide this for update to the devices 1. It will be appreciated that the processing system 1610 may therefore be a server or the like.

5 This allows the configuration data to be uploaded from the server either to a user's end station 1603, such as a desk top computer, lap top, Internet terminal or the like, or alternatively allows transfer from the server via the communications network 1602, 1604, such as the Internet. It will be appreciated that any suitable communications system can be used such as wireless links, wi-fi connections, or the like.

10 In any event, an example of the process of updating the measuring device 1 will now be described in more detail with reference to Figure 17. In this example, at step 1700 the base station 1600 determines that there is a change in the regulatory status of features implemented within a certain region. As mentioned above this could occur for example following approval by the TGA of new features.

15 The base station 1600 uses the change in regulatory status to determine new features available at step 1710, before determining an identifier associated with each measuring device 1 to be updated at step 1720. As changes in regulatory approval are region specific, this is typically achieved by having the base station 1600 access database 1611 including details of the regions in which each measuring device sold are used. The database 1611 includes the identifier for each measuring device 1, thereby  
20 allowing the identifier of each measuring device to be updated to be determined.

At step 1730, the base station 1600 determines the existing configuration data, typically from the database 1611, for a next one of the measuring devices 1, before modifying the configuration data to implement the new features at step 1740. The configuration data is then encrypted utilising a key associated with the identifier. The key may be formed from a unique prime number associated with  
25 the serial number, or partially derived from the serial number, and is typically stored in the database 1611, or generated each time it is required using a predetermined algorithm.

At step 1760 the encrypted configuration data is transferred to the measuring device 1 as described above.

At step 1770 when the device restarts and the first processing system 10 is activated, the first  
30 processing system 10 determines the encryption key, and uses this to decrypt the configuration data. This may be achieved in any one of a number of ways, such as by generating the key using the serial number or other identifier, and a predetermined algorithm. Alternatively, this may be achieved by

accessing a key stored in the memory 21. It will be appreciated that any form of encryption may be used, although typically strong encryption is used, in which a secret key is used to both encrypt and decrypt the configuration data, to thereby prevent fraudulent alteration of the configuration by users, as will be explained in more detail below.

- 5 At step 1780, the first processing system 10 activates software features within the second processing system 17 using the decrypted configuration data.

It will therefore be appreciated that this provides a mechanism for automatically updating the features available on the measuring device. This may be achieved either by having the second processing system 17 receive new firmware from the processing system 10, or by activating firmware already  
10 installed on the second processing system 17, as described above.

As an alternative to performing this automatically when additional features are approved for use, the process can be used to allow features to be activated on payment of a fee. In this example, a user may purchase a measuring device 1 with limited implemented functionality. By payment of a fee, additional features can then be activated as and when required by the user.

- 15 In this example, as shown in Figure 18, when the user selects an inactive feature at step 1800, the first processing system 10 will generate an indication that the feature is unavailable at step 1810. This allows the user to select an activate feature option at step 1820, which typically prompts the user to provide payment details at step 1830. The payment details are provided to the device manufacturer in some manner and may involve having the user phone the device manufacturer, or alternatively enter  
20 the details via a suitable payment system provided via the Internet or the like.

At step 1840, once the payment is verified, the process can move to step 1720 to allow an automatic update to be provided in the form of a suitable configuration data. However, if payment details are not verified the process ends at 1850.

- It will be appreciated by a person skilled in the art that encrypting the configuration data utilising a  
25 unique identifier means that the configuration data received by a measuring device 1 is specific to that measuring device. Accordingly, the first processing system 10 can only interpret the content of a configuration data if it is both encrypted and decrypted utilising the correct key. Accordingly, this prevents users exchanging configuration data, or attempting to re-encrypt a decrypted file for transfer to a different device.

- 30 It will be appreciated that in addition to, or as an alternative to simply specifying features in the configuration data, it may be necessary to upload additional firmware to the second processing system

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17. This can be used for example, to implement features that could not be implemented using the firmware shipped with the measuring device 1.

In this example, it would be typical for the configuration data to include any required firmware to be uploaded, allowing this to be loaded into the second processing system 17, using the first processing system 10. This firmware can then either be automatically implemented, or implemented in accordance with the list of available features provided in the configuration data.

It will be appreciated that this provides a mechanism for updating and/or selectively activating or deactivating features, such as measuring protocols, impedance analysis algorithms, reports interpreting measured results, or the like. This can be performed to ensure the measuring device conforms to existing TGA or FDA approvals, or the like.

### Housing

In order to provide a housing configuration with suitable electrical isolation for the subject an arrangement similar to that shown in Figure 19 can be used.

In this example the measuring device 1 is provided in a housing 70 which includes a touch screen 71, forming the I/O device 22, together with three respective circuit boards 72, 73, 74. In this instance the digital electronics including the second processing system 17 and the first processing system 10 are provided on the circuit board 72. The circuit board 73 is an analogue circuit board and includes the ADCs 37, 38, the DAC 39. A separate power supply board is then provided at 74. The supply board typically includes an integrated battery, allowing the measuring device 1 to form a portable device.

It is also typical housing electrical/magnetic shielding from the external environment, and accordingly, the housing is typically formed from a mu-metal, or from aluminium with added magnesium.

Persons skilled in the art will appreciate that numerous variations and modifications will become apparent. All such variations and modifications which become apparent to persons skilled in the art, should be considered to fall within the spirit and scope that the invention broadly appearing before described.

Thus, for example, it will be appreciated that features from different examples above may be used interchangeably where appropriate. Furthermore, whilst the above examples have focussed on a subject such as a human, it will be appreciated that the measuring device and techniques described

above can be used with any animal, including but not limited to, primates, livestock, performance animals, such race horses, or the like.

The above described processes can be used for diagnosing the presence, absence or degree of a range of conditions and illnesses, including, but not limited to oedema, lymphodema, body composition, or the like.

It will also be appreciated above described techniques, such as electrode identification, device updates and the like may be implemented using devices that do not utilise the separate first processing system 10 and second processing system 17, but rather use a single processing system 2, or use some other internal configuration.

Additionally, the end station 1603 can effectively perform any one or more of tasks performed by the first processing system 10 in the examples throughout the specification. Accordingly, the device could be provided without the first processing system 10, with the functionality usually performed by the first processing system 10 being performed by an end station 1603. In this arrangement, the end station 1603 therefore effectively forms part or all of the first processing system 10. This allows the measuring device 1 to be provided including only the second processing system 17 coupled directly to the external interface 23 to allow the measuring device 1 to be controlled by the end station 1603. This would typically be achieved via the use of suitable applications software installed on the end station 1603.



## THE CLAIMS

- 1) Apparatus for performing impedance measurements on a subject, the apparatus including:
  - a) a first processing system for:
    - i) determining an impedance measurement procedure; and,
    - ii) selecting instructions corresponding to the measurement procedure; and,
  - b) a second processing system for:
    - i) generating, using the instructions, control signals, the control signals being used to apply one or more signals to the subject;
    - ii) receiving an indication of the one or more signals applied to the subject;
    - iii) receiving an indication of one or more signals measured across the subject;
    - iv) performing, using the instructions, at least preliminary processing of the indications to thereby allow impedance values to be determined.
- 2) Apparatus according to claim 1, wherein the method includes, transferring the instructions from the first processing system to the second processing system.
- 3) Apparatus according to claim 1 or claim 2, wherein the method includes, selecting the instructions using configuration data.
- 4) Apparatus according to claim 3, wherein the method includes, receiving the configuration data from a remote processing system.
- 5) Apparatus according to any one of the claims 1 to 4, wherein the instructions are in the form of at least one of:
  - a) firmware; and,
  - b) embedded systems.
- 6) Apparatus according to any one of the claims 1 to 5, wherein the second processing system is an FPGA.
- 7) Apparatus according to any one of the claims 1 to 6, wherein the apparatus includes an input device, and wherein the first processing system is coupled to the input device to thereby determine the impedance measurement procedure in accordance with input commands from an operator.
- 8) Apparatus according to any one of the claims 1 to 7, wherein the first processing system includes a store for storing at least one profile, the at least one profile representing a predetermined impedance measurement procedure.
- 9) Apparatus according to any one of the claims 1 to 8, wherein the control signals represent a sequence of predetermined electrical signals, the sequence being dependent on the selected impedance measurement type.
- 10) Apparatus according to any one of the claims 1 to 9, wherein the apparatus includes:
  - a) a current ADC for:

- i) receiving signals from a current circuit; and,
  - ii) providing the indication of the one or more signals applied to the subject to the second processing system; and,
  - b) a voltage ADC for:
    - i) receiving signals from a voltage circuit; and,
    - ii) providing the indication of the one or more signals measured from the subject to the second processing system.
- 11) Apparatus according to claim 10, wherein the apparatus includes at least one buffer circuit for:
- a) receiving voltage signals from a voltage electrode;
  - b) filtering and amplifying the voltage signals; and,
  - c) transferring the filtered and amplified voltage signals to the voltage ADC via a differential amplifier.
- 12) Apparatus according to claim 10 or claim 11, wherein the apparatus includes a current source circuit for:
- a) receiving one or more control signals;
  - b) filtering and amplifying the control signals to thereby generate one or more current signals;
  - c) applying the current signals to a current electrode; and,
  - d) transferring an indication of the applied signals to the current ADC.
- 13) Apparatus according to any one of the claims 1 to 12, wherein the apparatus includes a control signal DAC for:
- a) receiving the control signals from the second processing system; and,
  - b) providing analogue control signals to a current circuit to thereby cause one or more current signals to be applied to the subject in accordance with the control signals.
- 14) Apparatus according to any one of the claims 1 to 13, wherein the second processing system is formed from first and second processing system portions, the first and second processing system portions being electrically isolated to thereby electrically isolate the subject from the first processing system.
- 15) Apparatus according to any one of the claims 1 to 14, wherein the apparatus includes:
- a) a measuring device including at least the first processing system; and,
  - b) one or more subject units, each subject unit including at least part of the second processing system.
- 16) Apparatus according to any one of the claims 1 to 15, wherein the apparatus includes at least two current electrodes for applying current signals to the subject, and a switch connected to the current electrodes for discharging the subject prior to measuring the induced voltage.
- 17) Apparatus according to any one of the claims 1 to 16, wherein the apparatus includes a housing having:

- a) a display;
  - b) a first circuit board for mounting at least one of the processing systems;
  - c) a second circuit board for mounting at least one of an ADC and a DAC; and,
  - d) a third circuit board for mounting a power supply.
- 5 18) Apparatus according to claim 17, wherein the housing is formed from at least one of a mu-metal and aluminium with added magnesium, to thereby provide electrical/magnetic shielding.
- 19) Apparatus according to any one of the claims 1 to 18, wherein the apparatus includes multiple channels, each channel being for performing impedance measurements using a respective set of electrodes.
- 10 20) Apparatus according to any one of the claims 1 to 19, wherein the apparatus is for:
- a) determining an electrode identifier associated with at least one electrode provided on the subject;
  - b) determining, using the electrode identifier, an electrode position indicative of the position of the at least one electrode on the subject; and,
  - 15 c) performing at least one impedance measurement using the electrode position.
- 21) Apparatus according to any one of the claims 1 to 20, wherein the apparatus is for:
- a) determining a parameter associated with at least one electrode lead; and,
  - b) causing at least one impedance measurement to be performed using the determined parameter.
- 20 22) Apparatus according to any one of the claims 1 to 21, wherein the apparatus is for:
- a) receiving configuration data, the configuration data being indicative of at least one feature;
  - b) determining, using the configuration data, instructions representing the at least one feature; and,
  - c) causing, using the instructions, at least one of:
  - 25 i) at least one impedance measurement to be performed; and,
  - ii) at least one impedance measurement to be analysed.
- 23) Apparatus according to any one of the claims 1 to 21, wherein the apparatus is for:
- a) causing a first signal to be applied to the subject;
  - b) determining at least one parameter relating to at least one second signal measured across the subject;
  - 30 c) comparing the at least one parameter to at least one threshold; and,
  - d) depending on the results of the comparison, selectively repeating steps (a) to (d) using a first signal having an increased magnitude.
- 24) A method of performing impedance measurements on a subject, the method including:
- 35 a) using a first processing system for:
  - i) determining an impedance measurement procedure; and,

- ii) selecting instructions corresponding to the measurement procedure; and,
- b) using a second processing system for:
  - i) generating, using the instructions, control signals, the control signals being used to apply one or more signals to the subject;
  - 5 ii) receiving an indication of the one or more signals applied to the subject;
  - iii) receiving an indication of one or more signals measured across the subject;
  - iv) performing, using the instructions, at least preliminary processing of the first and second data to thereby allow impedance values to be determined.

25) A method according to claim 24, wherein the method is performed using the apparatus according to any one of the claims 1 to 23.

26) A method of diagnosing conditions in a subject, the method including, in a processing system:

- a) using a first processing system for:
  - i) determining an impedance measurement procedure; and,
  - ii) selecting instructions corresponding to the measurement procedure; and,
- 15 b) using a second processing system for:
  - i) generating, using the instructions, control signals, the control signals being used to apply one or more signals to the subject;
  - ii) receiving an indication of the one or more signals applied to the subject;
  - iii) receiving an indication of one or more signals measured across the subject;
  - 20 iv) performing, using the instructions, at least preliminary processing of the first and second data to thereby allow impedance values to be determined.

27) A method according to claim 26, wherein the method is performed using the apparatus according to any one of the claims 1 to 23.

28) Apparatus for connecting measurement apparatus to an electrode, the apparatus including:

- 25 a) a housing having a connector for coupling the housing to an electrode; and,
- b) a circuit mounted in the housing, the circuit being electrically coupled to the electrode using the connector, and being coupled to a lead, the circuit being for at least one of:
  - i) generating predetermined electrical signals in accordance with control signals received from the measurement apparatus;
  - 30 ii) providing an indication of electrical signals applied to the electrode; and,
  - iii) providing an indication of electrical signals measured at the electrode.

29) Apparatus according to claim 28, wherein the circuit is provided on a circuit board having an electrical contact, and wherein in use the connector urges at least part of the electrode into abutment with the electrical contact.

30) Apparatus according to claim 29, wherein the connector includes a biased arm.

31) Apparatus according to any one of the claims 28 to 30, wherein the circuit includes a buffer circuit for:

- a) sensing voltage signals at the electrode;
- b) filtering and amplifying the voltage signals; and,
- 5 c) transferring the filtered and amplified voltage signals to the measurement apparatus.

32) Apparatus according to any one of the claims 28 to 30, wherein the circuit includes a current source circuit for:

- a) receiving one or more control signals;
- b) filtering and amplifying the control signals to thereby generate one or more current signals;
- 10 c) applying the current signals to the electrode pad; and,
- d) transferring an indication of the applied signals to the measurement apparatus.

33) Apparatus according to any one of the claims 28 to 32, wherein the apparatus further comprises an electrode, the electrode including:

- a) an electrode substrate; and,
- 15 b) a conductive material for electrically coupling the electrode to the subject.

34) Apparatus according to claim 33, wherein the electrode substrate is electrically conductive, and wherein in use the connector couples the circuit to the electrode substrate.

35) Apparatus according to any one of the claims 28 to 34, wherein the housing includes curved edges.

20 36) Apparatus according to any one of the claims 28 to 34, wherein the housing is formed from a material that, at least one of:

- a) has a low coefficient of friction; and,
- b) is resilient.

37) Apparatus according to any one of the claims 28 to 36, wherein the apparatus is used with apparatus according to any one of the claims 1 to 23.

38) A method of performing impedance measurements on a subject, the method including, in a processing system:

- a) determining an encoded value associated with at least one electrode lead; and,
- b) causing at least one impedance measurement to be performed using the encoded value.

39) A method according to claim 38, wherein the encoded value is used for calibration.

40) A method according to claim 38 or claim 39, wherein the encoded value is determined from a resistance value.

41) A method according to any one of the claims 38 to 40, wherein the encoded value is indicative of an identity of the lead.

35 42) A method according to any one of the claims 38 to 41, wherein the method includes, in the processing system, controlling the current applied to the subject using the determined resistance.

- 43) A method according to any one of the claims 38 to 42, wherein the encoded value is a lead identifier, and wherein the method includes, in the processing system:
- a) determining, using the lead identifier, an impedance measurement procedure; and,
  - b) causing the determined impedance measurement procedure to be performed.
- 5 44) A method according to claim 43, wherein the method includes, in the processing system:
- a) comparing the determined identity to one or more predetermined identities; and,
  - b) determining the impedance of the subject in response to a successful comparison.
- 45) A method according to claim 43, wherein the method includes, in the processing system:
- a) determining the lead identifier associated with the at least one electrode lead;
  - 10 b) determining, using the lead identifier, a lead usage;
  - c) comparing the lead usage to a threshold; and,
  - d) in accordance with the results of the comparison, at least one of:
    - i) generating an alert;
    - ii) terminating an impedance measurement procedure; and,
    - 15 iii) performing an impedance measurement procedure.
- 46) A method according to any one of the claims 38 to 45, wherein the method includes, in the processing system, at least one of:
- a) processing electrical signals measured from the subject to thereby determine one or more impedance values; and,
  - 20 b) processing determined impedance values.
- 47) A method according to any one of the claims 38 to 46, wherein the encoded value is stored in a store.
- 48) Apparatus for performing impedance measurements on a subject, the apparatus including:
- a) at least one lead for connecting to electrodes coupled to the subject, the at least one lead including an encoded value; and,
  - 25 b) a processing system coupled to the at least one lead for:
    - i) determining the encoded value; and,
    - c) causing at least one impedance measurement to be performed using the encoded value.
- 49) Apparatus according to claim 44, wherein the apparatus is for performing the method of any one of the claims 38 to 47.
- 30 50) A method of performing impedance measurements on a subject, the method including, in a processing system:
- a) determining an electrode identifier associated with at least one electrode provided on the subject;
  - 35 b) determining, using the electrode identifier, an electrode position indicative of the position of the at least one electrode on the subject; and,

c) causing at least one impedance measurement to be performed using the electrode position.

51) A method according to claim 50, wherein the impedance measurement is performed using at least four electrodes, each having a respective identifier, and wherein the method includes, in the processing system:

- a) determining an electrode identifier for each electrode;
- b) determining, using each electrode identifier, an electrode position for each electrode; and,
- c) performing at least one impedance measurement using the electrode positions.

52) A method according to claim 51, wherein the method includes, in the processing system:

- a) causing signals to be applied to at least two of the electrodes in accordance with the determined electrode positions; and,
- b) causing signals to be measured from at least two of the electrodes in accordance with the determined electrode positions.

53) A method according to any one of the claims 50 to 52, wherein the method includes, in the processing system, determining the electrode identifier for an electrode by selectively measuring the conductivity between one or more contacts provided on the electrode.

54) A method according to any one of the claims 50 to 53, wherein the processing system is coupled to a signal generator and a sensor, and wherein the method includes, in the processing system:

- a) selectively interconnecting the signal generator and at least two electrode leads, to thereby allow signals to be applied to the subject; and,
- b) selectively interconnecting the sensor at least two electrode leads to thereby allow a signal to be measured from the subject.

55) A method according to claim 54, wherein the method includes, in the processing system controlling a multiplexer to thereby selectively interconnect the leads and at least one of the signal generator and the sensor.

56) A method according to any one of the claims 50 to 55, wherein the at least one electrode includes visual indicia indicative of the position of the at least one electrode on the subject.

57) Apparatus for performing impedance measurements on a subject, the apparatus including a processing system for:

- a) determining an electrode identifier associated with at least one electrode provided on the subject;
- b) determining, using the electrode identifier, an electrode position indicative of the position of the at least one electrode on the subject; and,
- c) causing at least one impedance measurement to be performed using the electrode position.

58) Apparatus according to claim 58, wherein the apparatus is for performing the method of any one of the claims 50 to 56.

59) A method for configuring a measuring device for measuring the impedance of a subject, the method including, in a processing system:

- a) receiving configuration data, the configuration data being indicative of at least one feature;
- b) determining, using the configuration data, instructions representing the at least one feature;
- 5 and,
- c) causing, at least in part using the instructions, at least one of:
  - i) impedance measurements to be performed; and,
  - ii) analysis of impedance measurements.

60) A method according to claim 59, wherein the configuration data includes the instructions.

10 61) A method according to claim 59 or claim 60, wherein the method includes, in the processing system:

- a) determining an indication of the at least one feature using the configuration data; and,
- b) determining the instructions using the indication of the at least one feature.

15 62) A method according to any one of the claims 59 to 61, wherein the method includes, in the processing system, decrypting the received configuration data.

63) A method according to claim 62, wherein the method includes, in the processing system:

- a) determining a device identifier associated with the measuring device;
- b) determining, using the device identifier, a key; and,
- c) decrypting the received configuration data using the key.

20 64) A method according to any one of the claims 59 to 63, wherein the processing system includes first and second processing systems, and wherein the method includes:

- a) in the first processing system, selecting the instructions using the configuration data; and,
- b) in the second processing system, generating the control signals using selected instructions.

25 65) A method according to claim 64, wherein the method includes, in the processing first system, at least one of:

- a) transferring the instructions to the second processing system; and,
- b) causing the second processing system to access the instructions from a store.

30 66) A method according to claim 65, wherein the method includes, in the processing system, receiving the configuration data from at least one of a computer system and a communications network.

67) A method according to any one of the claims 59 to 66, wherein the method includes, in the processing system:

- a) determining if a feature selected by a user is available;
- b) if the feature is not available, determining if the user wishes to enable the feature; and,
- 35 c) if the user wishes to enable the feature, causing configuration data to be received.

68) A method according to claim 67, wherein the method includes, in the processing system:



- a) causing the user to provide a payment to a device provider; and,
- b) receiving the configuration data in response to payment.

69) Apparatus for configuring a measuring device for measuring the impedance of a subject, the apparatus including a processing system for:

- a) receiving configuration data, the configuration data being indicative of at least one feature;
- b) determining, using the configuration data, instructions representing the at least one feature; and,
- c) causing, at least in part using the instructions, at least one of:
  - i) impedance measurements to be performed; and,
  - ii) analysis of impedance measurements.

70) Apparatus according to claim 69, wherein the apparatus is for performing the method of any one of the claims 59 to 68.

71) A method for configuring a measuring device for measuring the impedance of a subject, the method including, in a computer system:

- a) determining configuration data required for a measuring device, the configuration data being indicative of at least one feature; ; and,
- b) causing the configuration data to be received by a processing system in the measuring device, the processing system being responsive to the configuration data to configure the measuring device to allow the at least one feature to be used.

72) A method according to claim 71, wherein the method includes, in the computer system:

- a) determining a device identifier, the device identifier being associated with the measuring device to be configured; and,
- b) using the device identifier to at least one of:
  - i) transfer the configuration data to the measuring device; and,
  - ii) encrypt the configuration data.

73) A method according to claim 71 or claim 72, wherein the method includes, in the computer system, determining the configuration data is required in response to at least one of:

- a) payment made by a user of the measuring device; and,
- b) approval of the feature.

74) A method according to claim 73, wherein the method includes, in the computer system:

- a) determining regulatory approval of the at least one feature in at least one region;
- b) determining at least one measuring device in the at least one region; and,
- c) configuring the at least one measuring device.

75) A method according to any one of the claims 71 to 74, wherein the method is used in the method of any one of the claims 59 to 68.

76) Apparatus for configuring a measuring device for measuring the impedance of a subject, the method including, in a computer system:

- a) determining configuration data required for a measuring device, the configuration data being indicative of at least one feature; ; and,
- b) causing the configuration data to be received by a processing system in the measuring device, the processing system being responsive to the configuration data to configure the measuring device to allow the at least one feature to be used.

77) Apparatus according to claim 76, wherein the apparatus is for performing the method of any one of the claims 71 to 75.

78) A method of performing impedance measurements on a subject, wherein the method includes, in a processing system:

- a) causing a first signal to be applied to the subject;
- b) determining at least one parameter relating to at least one second signal measured across the subject;
- c) comparing the at least one parameter to at least one threshold; and,
- d) depending on the results of the comparison, selectively repeating steps (a) to (d) using a first signal having an increased magnitude.

79) A method according to claim 78, wherein the method includes, in the processing system:

- a) determining an animal type of the subject; and,
- b) selecting the threshold in accordance with the animal type.

80) A method according to claim 78 or claim 79, wherein the threshold is indicative of at least one of:

- a) a minimum second signal magnitude; and,
- b) a minimum signal to noise ratio for the second signal.

81) A method according to any one of the claims 78 to 80, wherein the method includes, in the processing system:

- a) determining at least one parameter relating to the at least one first signal;
- b) comparing the at least one parameter to at least one threshold; and,
- c) selectively terminating impedance measurements depending on the results of the comparison.

82) A method according to claim 81, wherein the threshold is indicative of a maximum first signal magnitude.

83) Apparatus for performing impedance measurements on a subject, wherein the apparatus includes a processing system for:

- a) causing a first signal to be applied to the subject;
- b) determining at least one parameter relating to at least one second signal measured across the subject;
- c) comparing the at least one parameter to at least one threshold; and,

d) depending on the results of the comparison, selectively repeating steps (a) to (d) using a first signal having an increased magnitude.'

84) Apparatus according to claim 83, wherein the apparatus further includes a variable magnitude current supply.

5 85) Apparatus according to claim 83 or claim 84, wherein the apparatus is for performing the method of any one of the claims 78 to 82.

86) A method of providing an electrode for use in impedance measurement procedures, the method including:

a) providing on a substrate:

10 i) a number of electrically conductive contact pads; and,  
ii) a corresponding number of electrically conductive tracks, each track extending from an edge of the substrate to a respective contact pad;

b) applying an insulating layer to the substrate, the insulating layer including a number of apertures, and being positioned to thereby overlay the tracks with at least a portion of each  
15 pad contact aligned with a respective aperture; and,

c) providing an electrically conductive medium in the apertures.

87) A method according to claim 86, wherein the electrically conductive medium is formed from a conductive gel.

88) A method according to claim 87, wherein the conductive gel is silver/silver chloride gel.

20 89) A method according to any one of the claims 86 to 88, wherein the method includes, providing a covering layer on the insulating layer to thereby cover the electrically conductive medium.

90) A method according to claim 89, wherein the insulating layer has an adhesive surface that releasably engages the covering layer.

91) A method according to any one of the claims 86 to 90, wherein the substrate is an elongate  
25 substrate, and wherein the method includes aligning the pad contacts along the length of the substrate.

92) A method according to any one of the claims 86 to 91, wherein the method includes providing the tracks and contact pads using at least one of:

a) screen printing;  
30 b) inkjet printing; and,  
c) vapour deposition.

93) A method according to any one of the claims 86 to 92, wherein the tracks and contact pads are formed from silver.

94) A method according to any one of the claims 86 to 93, wherein the method includes forming the  
35 substrate by:

a) overlaying a plastic polymer with a shielding material; and,

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b) covering the shielding material with an insulating material.

95) An electrode for use in impedance measurement procedures, the electrode including:

a) a substrate having provided thereon:

i) a number of electrically conductive contact pads; and,

ii) a corresponding number of electrically conductive tracks, each track extending from an edge of the substrate to a respective contact pad;

b) an insulating layer provided on the substrate, the insulating layer including a number of apertures, and being positioned to thereby overlay the tracks with at least a portion of each pad contact aligned with a respective aperture; and,

c) an electrically conductive medium provided in the apertures.

96) An electrode according to claim 95, wherein the electrode is formed using the method of any one of the claims 86 to 94.

97) A method for use in diagnosing conditions in a subject, the method including, in a processing system:

a) determining an encoded value associated with at least one electrode lead; and,

b) causing at least one impedance measurement to be performed using the encoded value.

98) A method for use in diagnosing conditions in a subject, the method including, in a processing system:

a) determining an electrode identifier associated with at least one electrode provided on the subject;

b) determining, using the electrode identifier, an electrode position indicative of the position of the at least one electrode on the subject; and,

c) causing at least one impedance measurement to be performed using the electrode position.

99) A method for use in diagnosing conditions in a subject, the method including, in a processing system:

a) receiving configuration data, the configuration data being indicative of at least one feature;

b) determining, using the configuration data, instructions representing the at least one feature; and,

c) causing the measuring device to perform, using the instructions, at least one of:

i) impedance measurements; and,

ii) analysis of impedance measurements.

100) A method for use in diagnosing conditions in a subject, the method including, in a processing system:

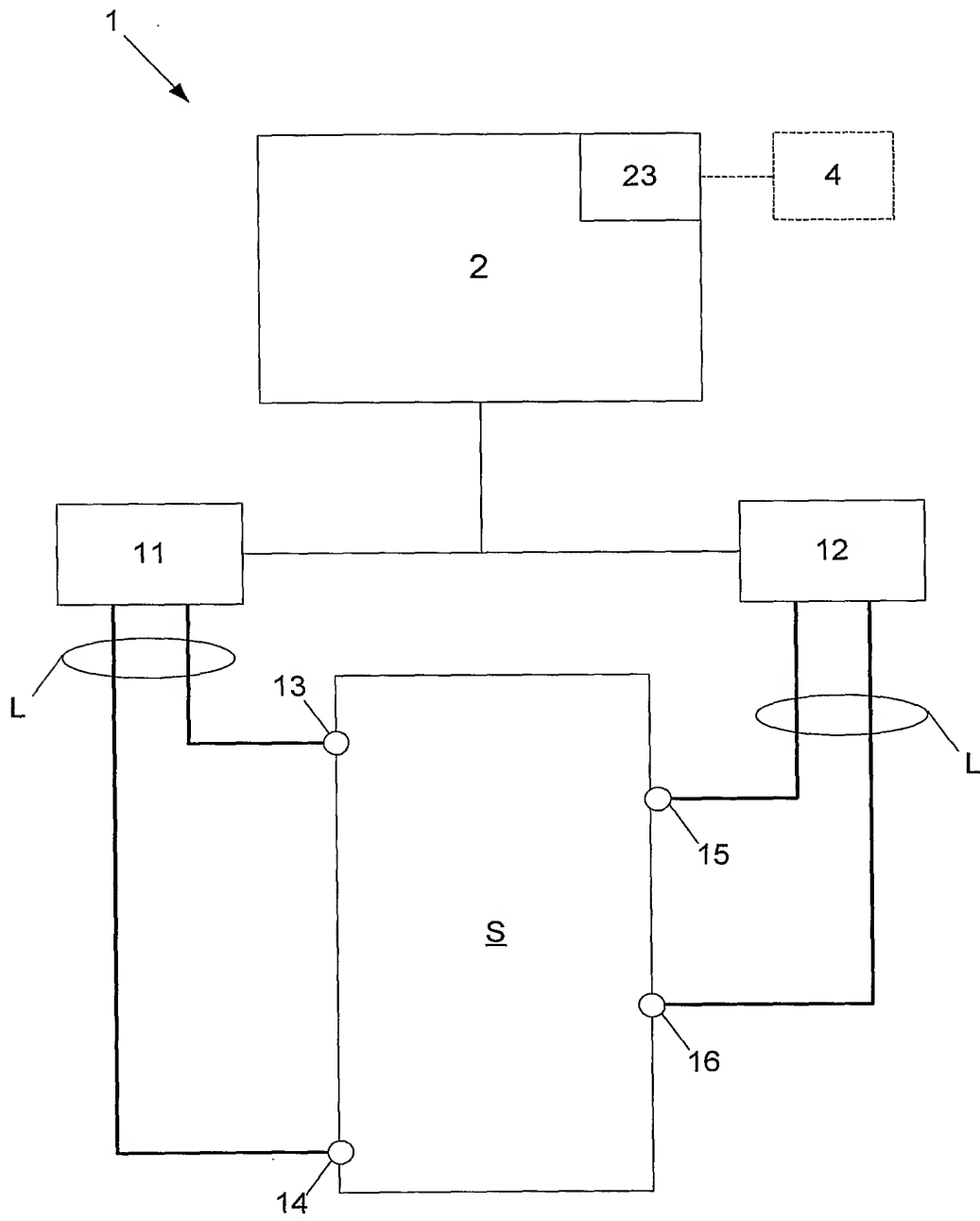
a) determining configuration data required for a measuring device, the configuration data being indicative of at least one feature; ; and,

- b) causing the configuration data to be received by a processing system in the measuring device, the processing system being responsive to the configuration data to configure the measuring device to allow the at least one feature to be used.

101) A method for use in diagnosing conditions in a subject, the method including, in a processing  
5 system:

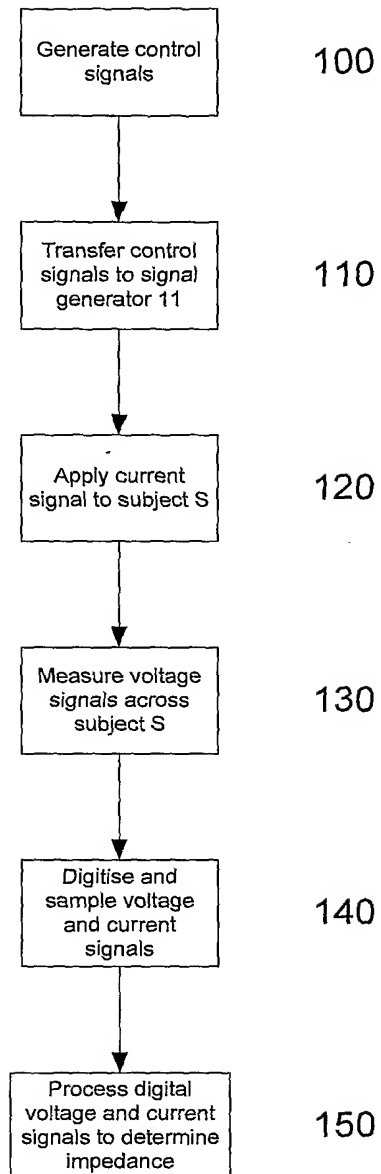
- a) causing a first signal to be applied to the subject;
- b) determining at least one parameter relating to at least one second signal measured across the subject;
- c) comparing the at least one parameter to at least one threshold; and,
- 10 d) depending on the results of the comparison, selectively repeating steps (a) to (d) using a first signal having an increased magnitude.

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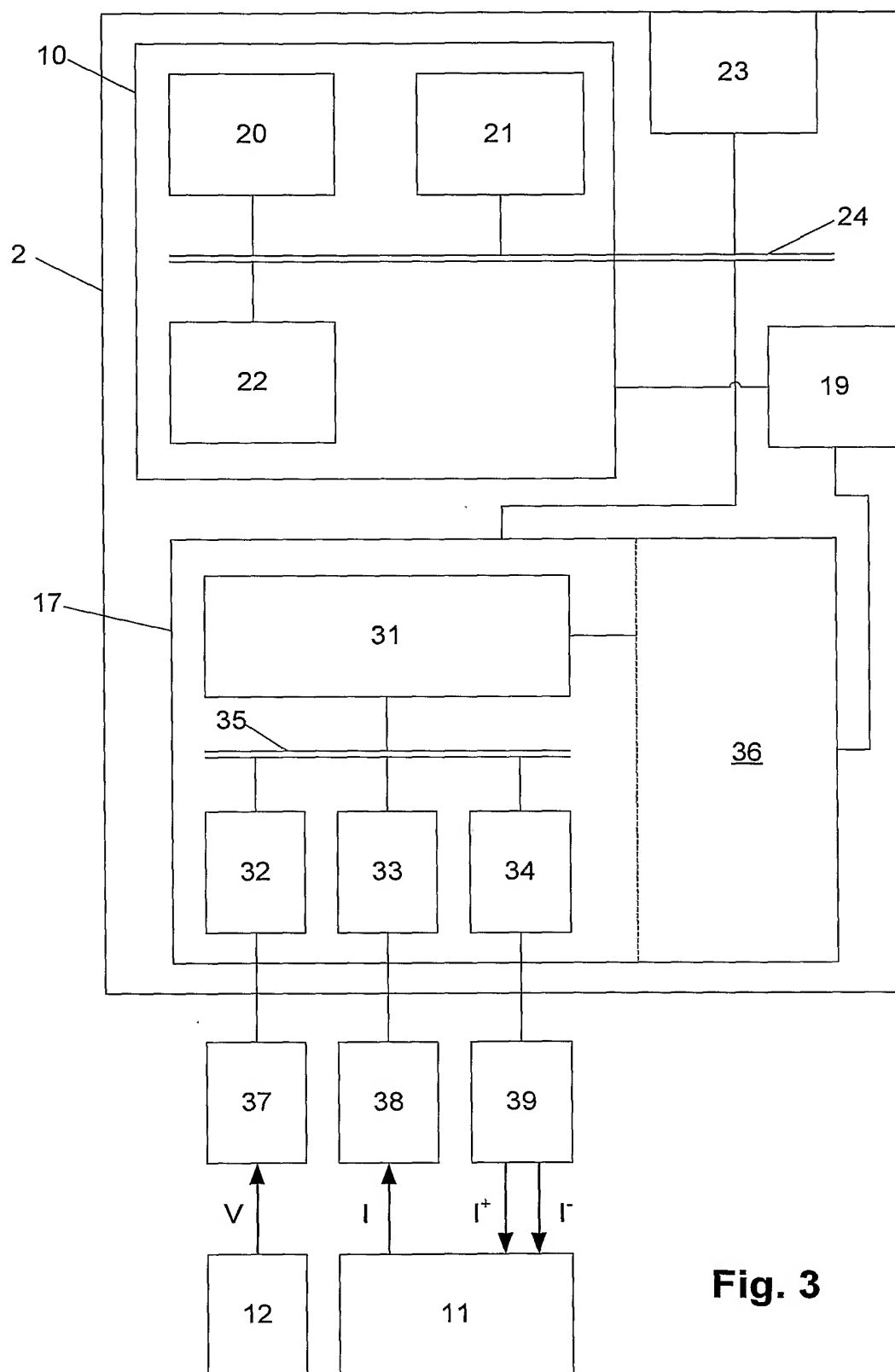


**Fig. 1**

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**Fig. 2**

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**Fig. 3**



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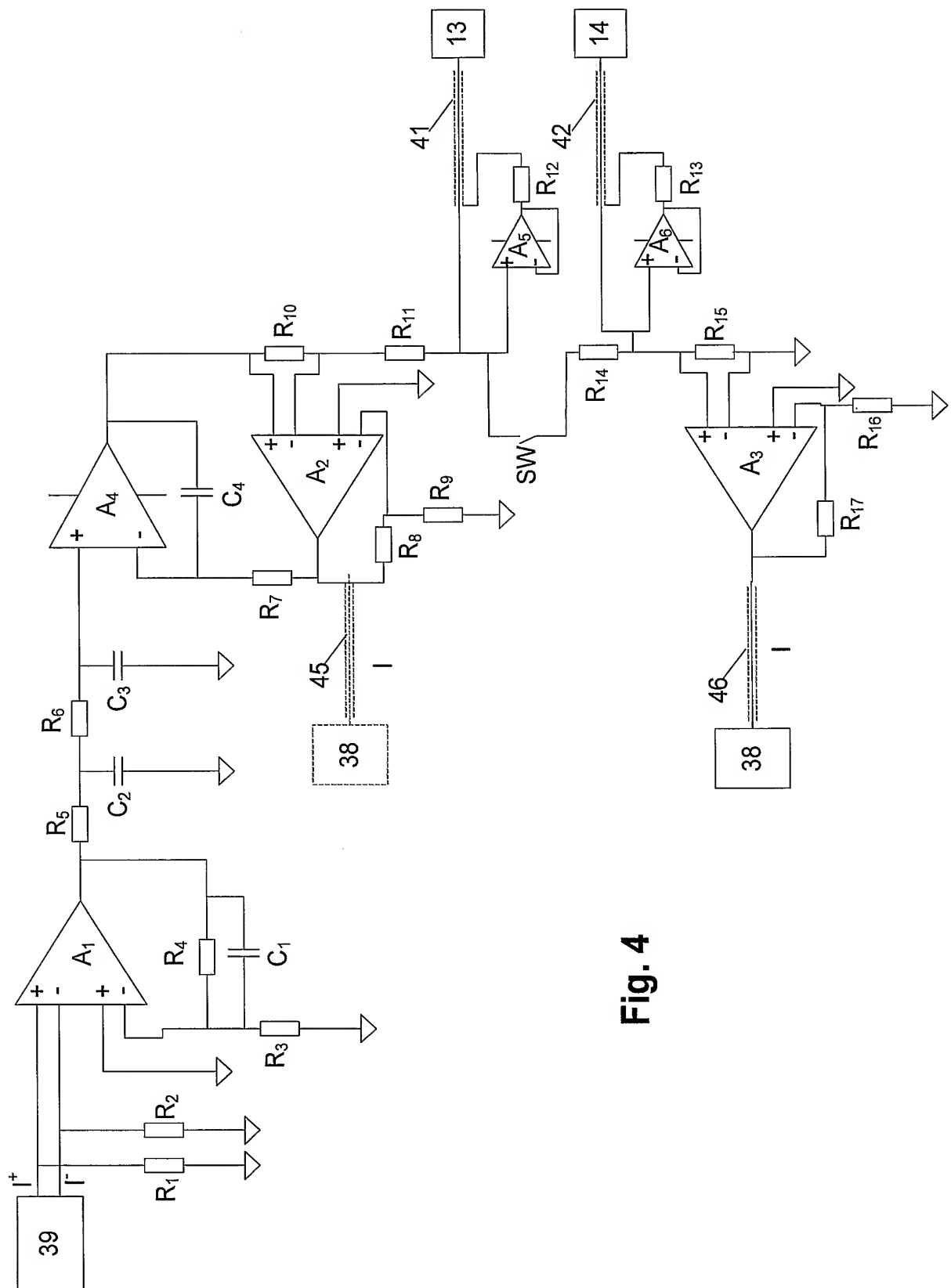


Fig. 4

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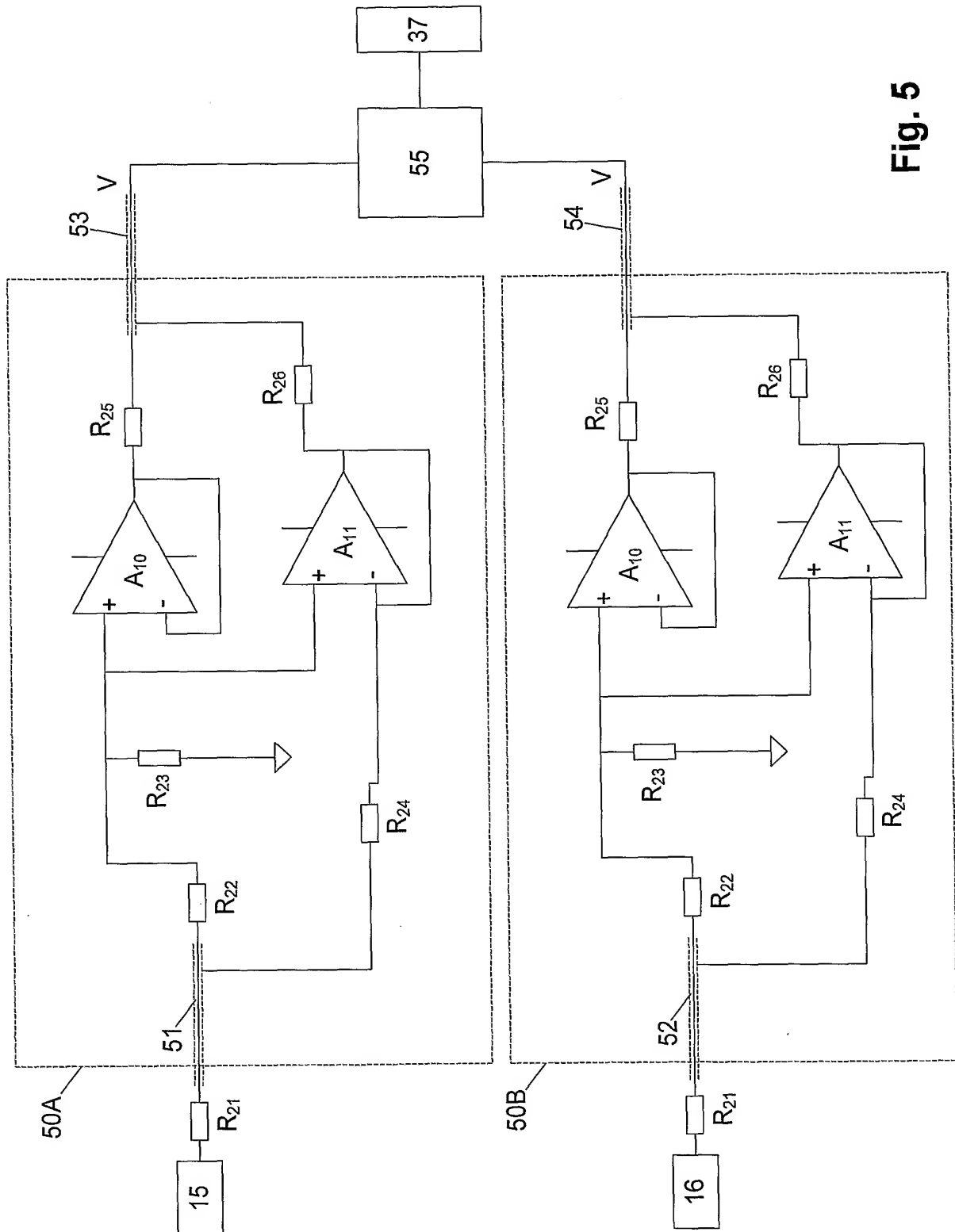


Fig. 5

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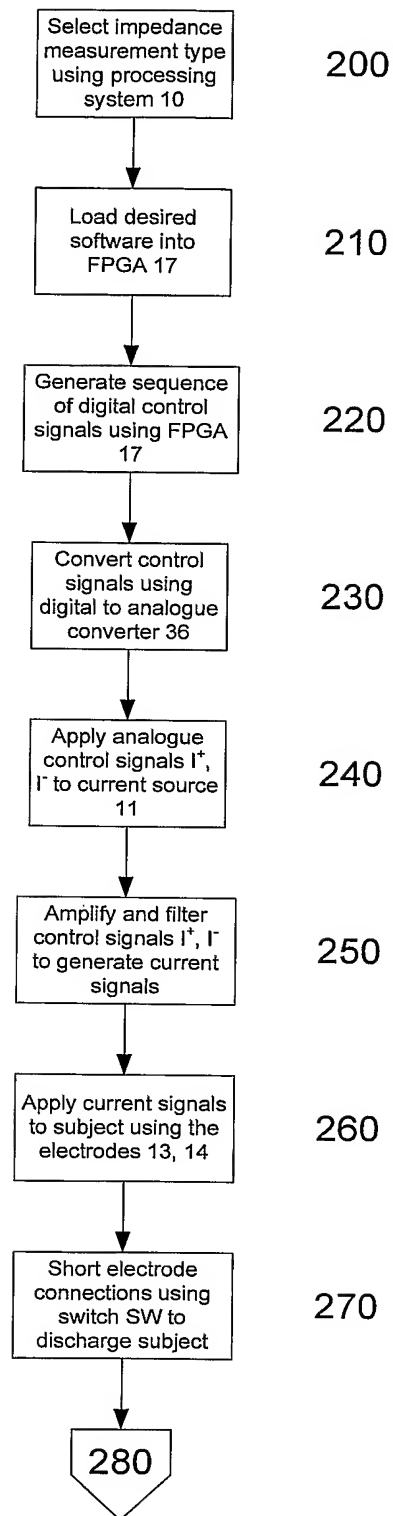
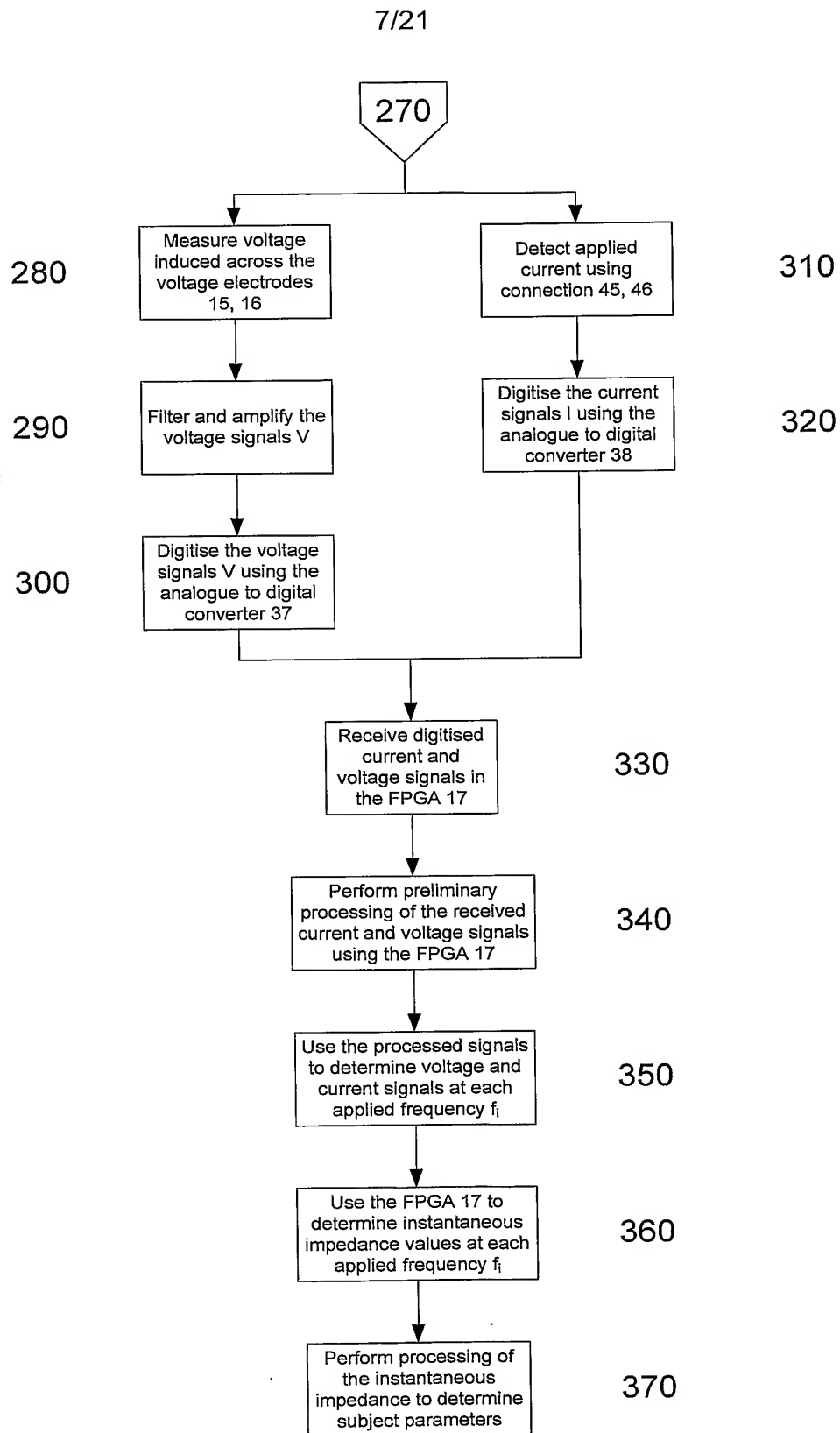
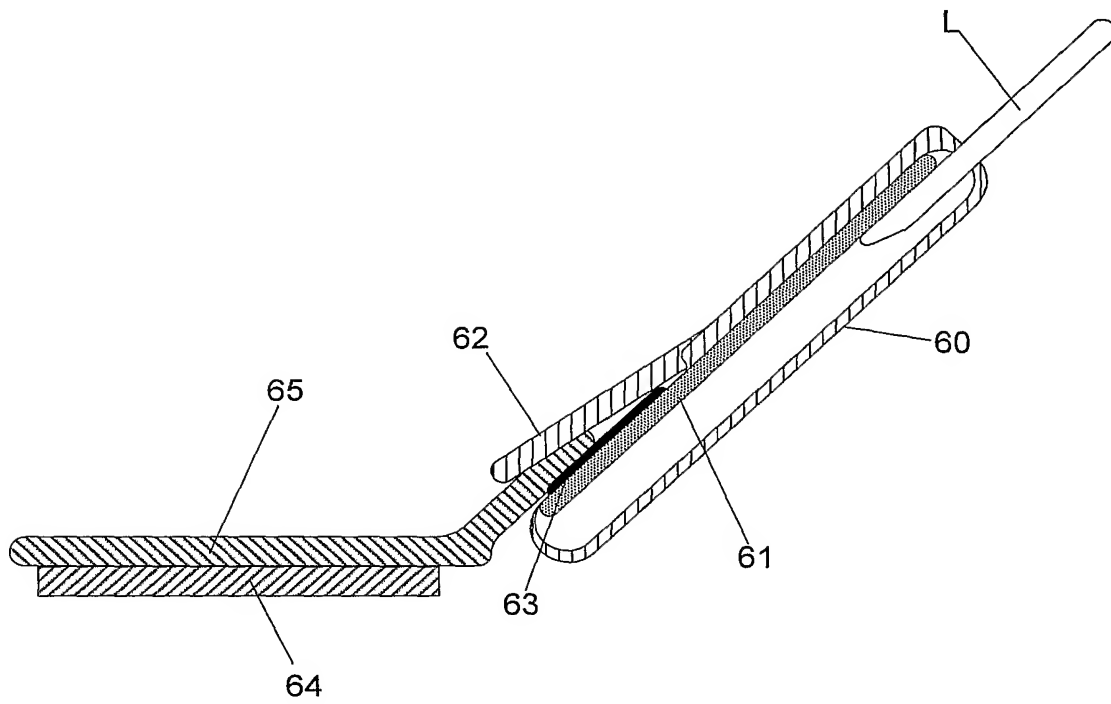


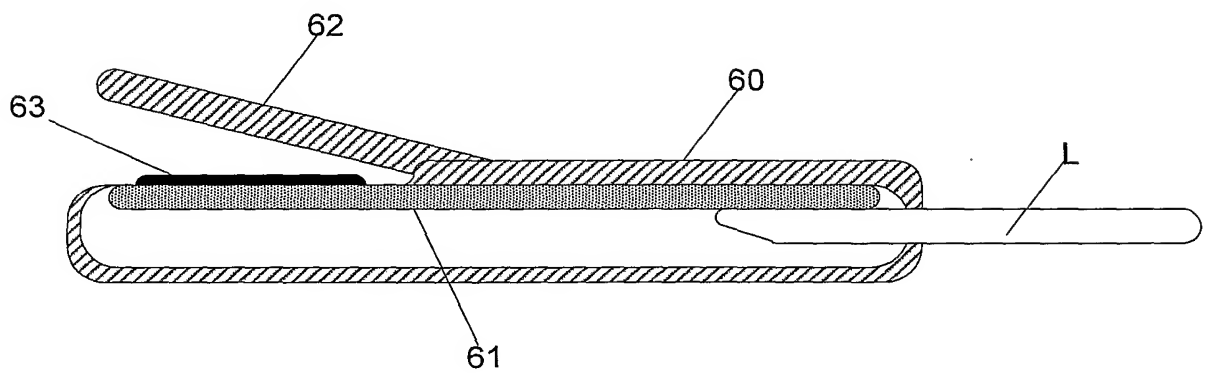
Fig. 6A

**Fig.6B**

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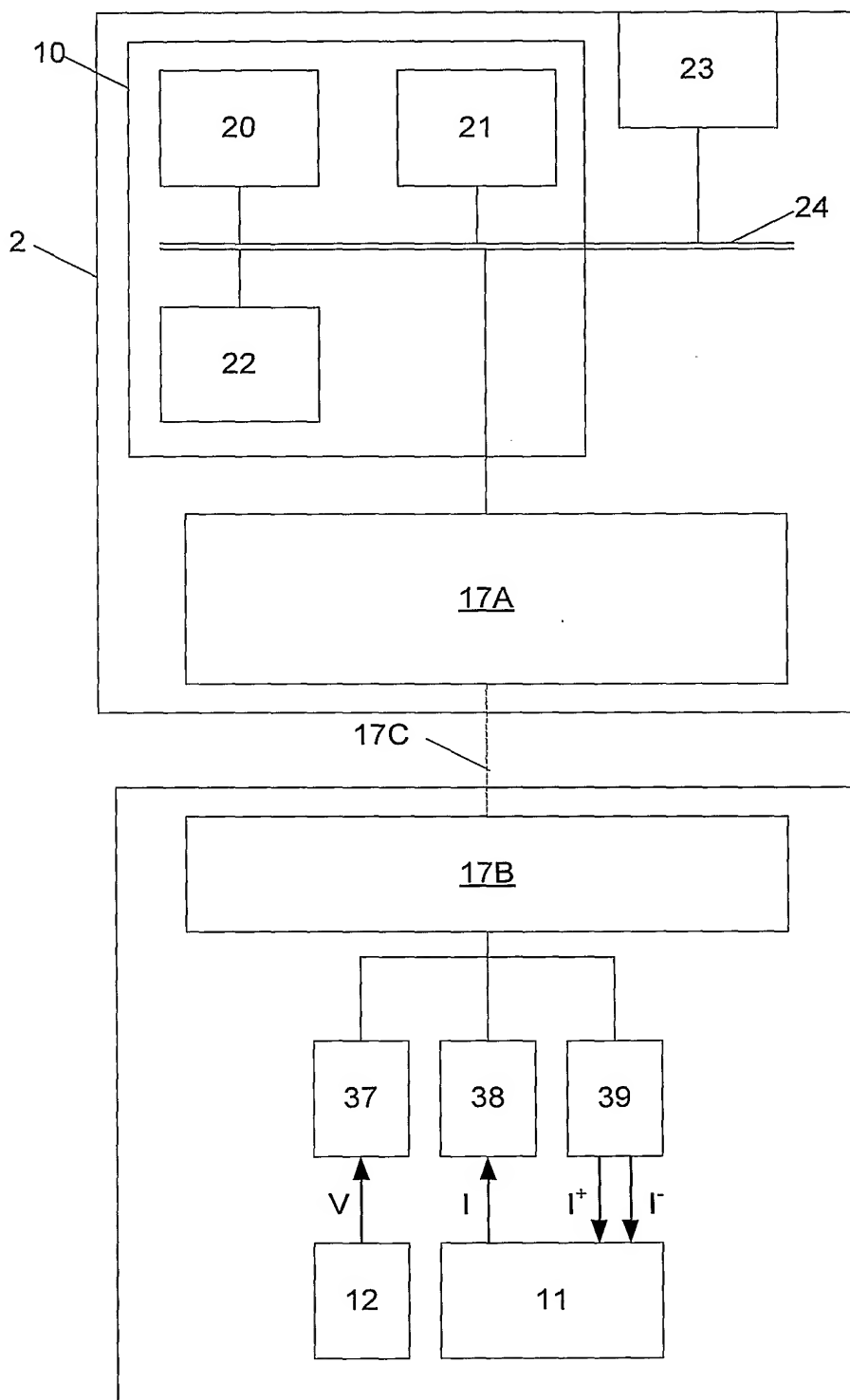


**Fig. 7A**

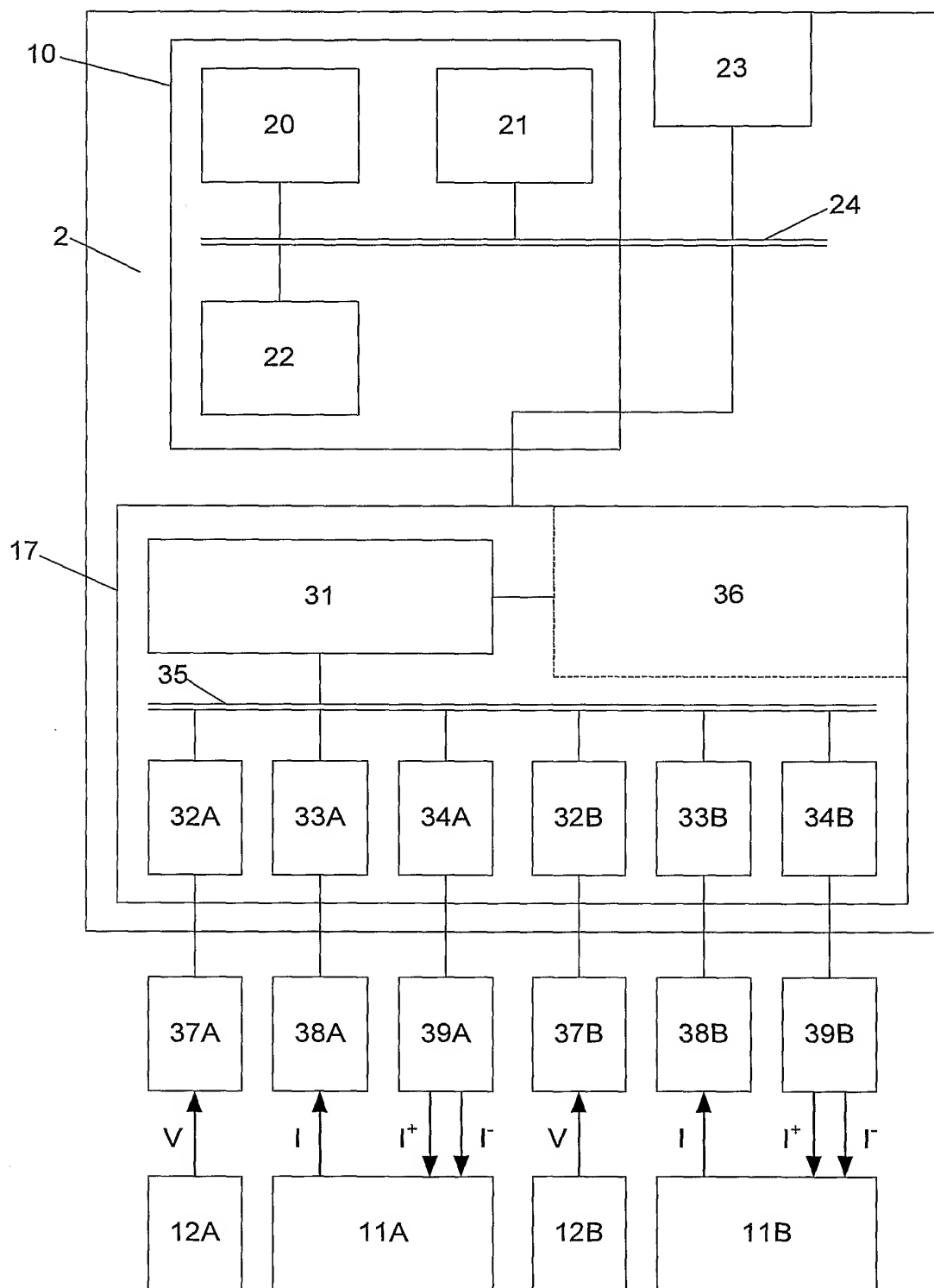


**Fig. 7B**

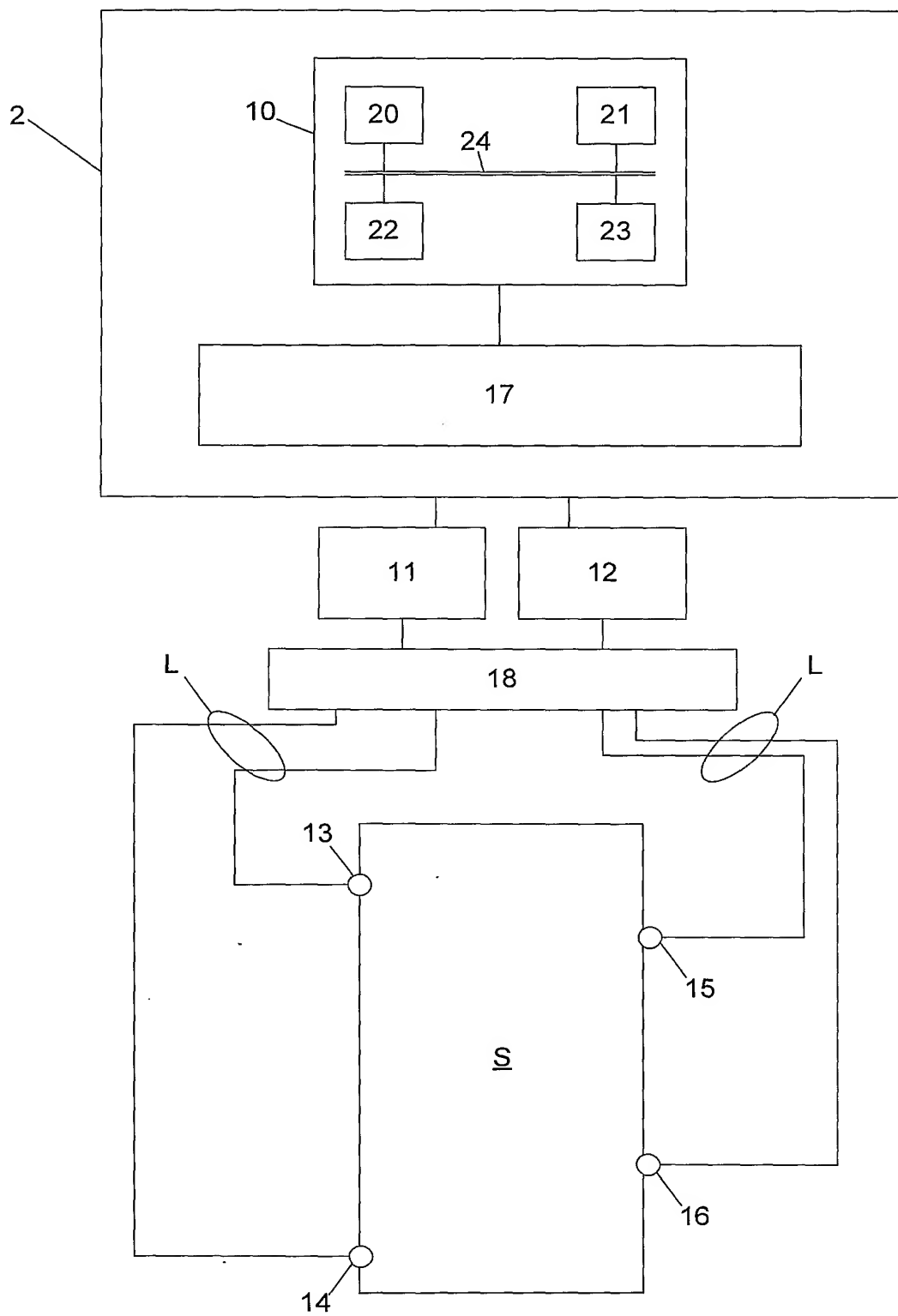
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**Fig. 8**

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**Fig. 9**

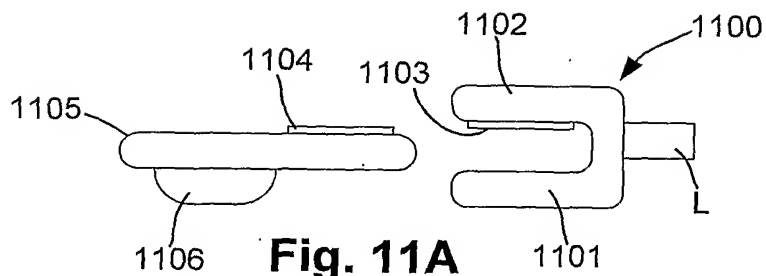
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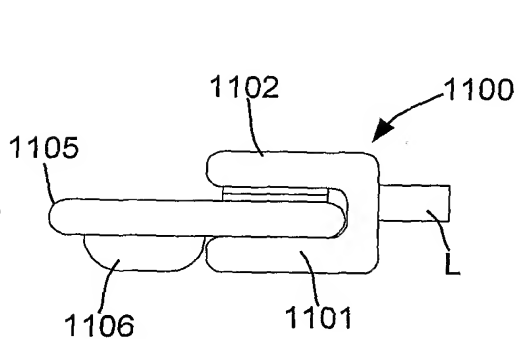
**Fig. 10**



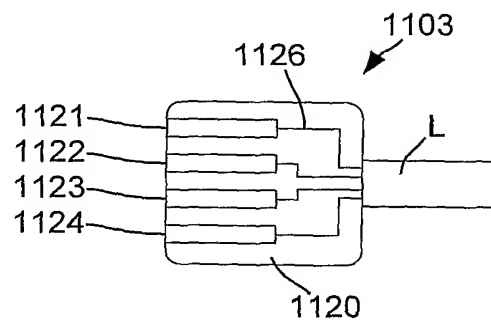
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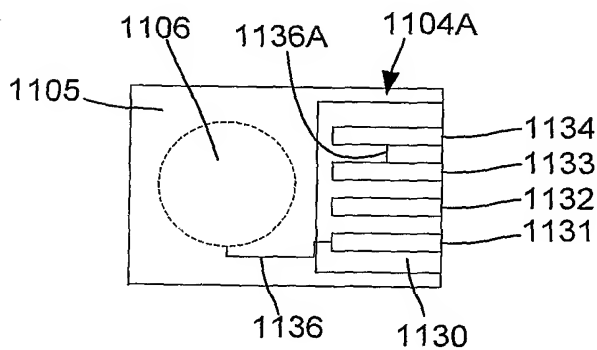
**Fig. 11A**



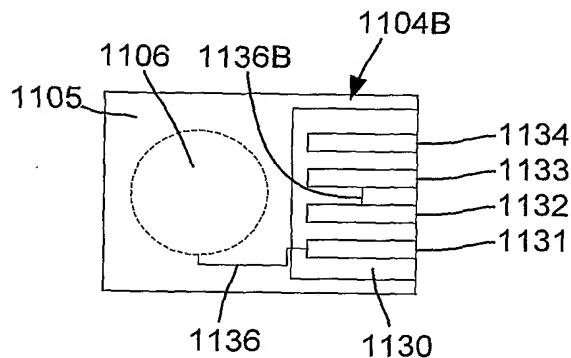
**Fig. 11B**



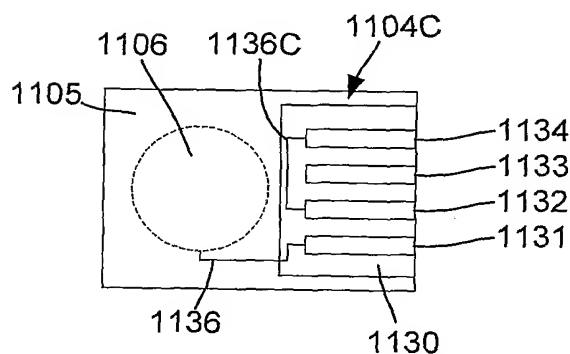
**Fig. 11C**



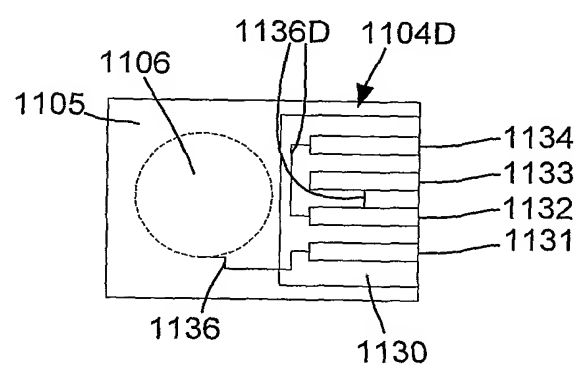
**Fig. 11D**



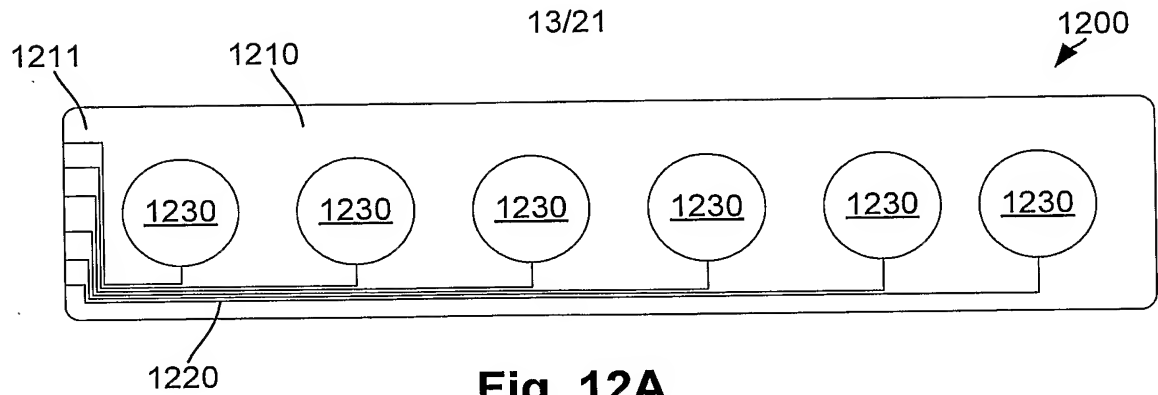
**Fig. 11E**



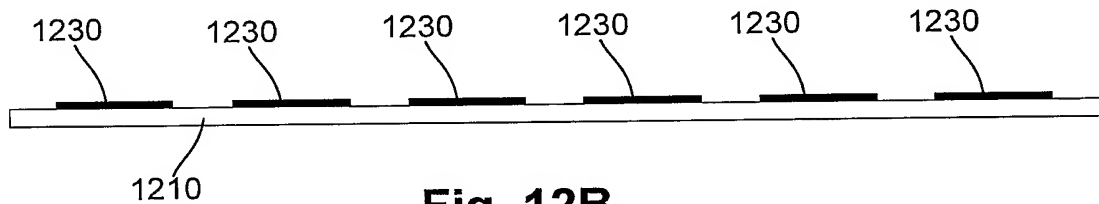
**Fig. 11F**



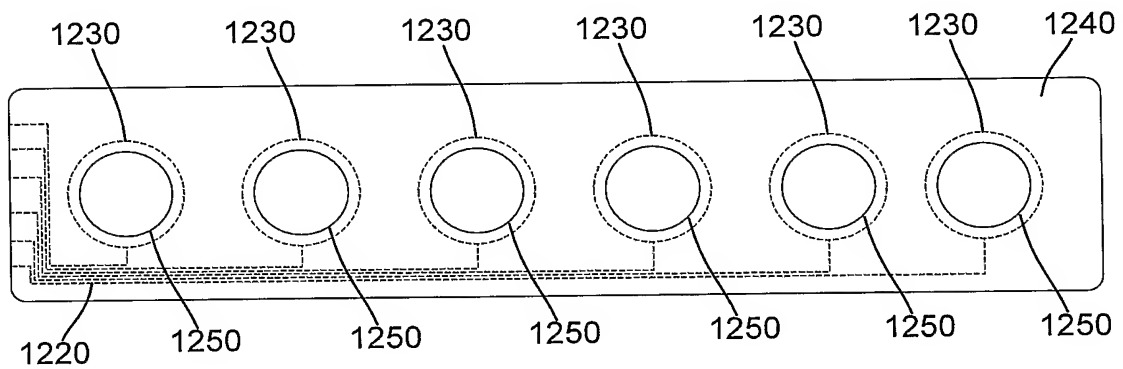
**Fig. 11G**



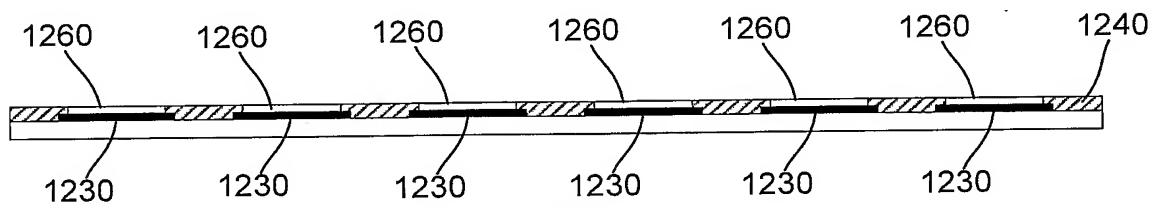
**Fig. 12A**



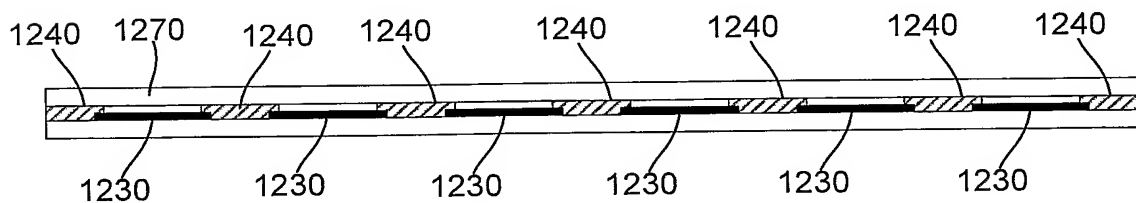
**Fig. 12B**



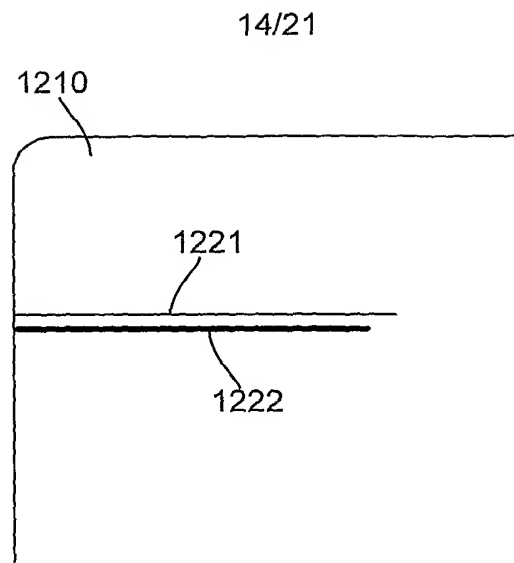
**Fig. 12C**



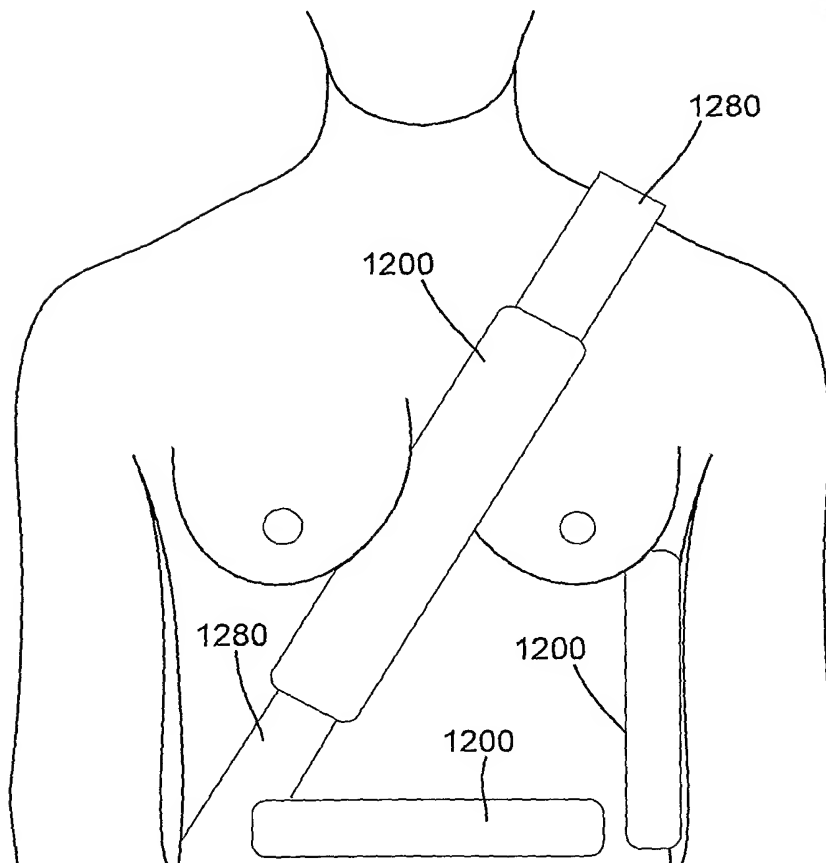
**Fig. 12D**



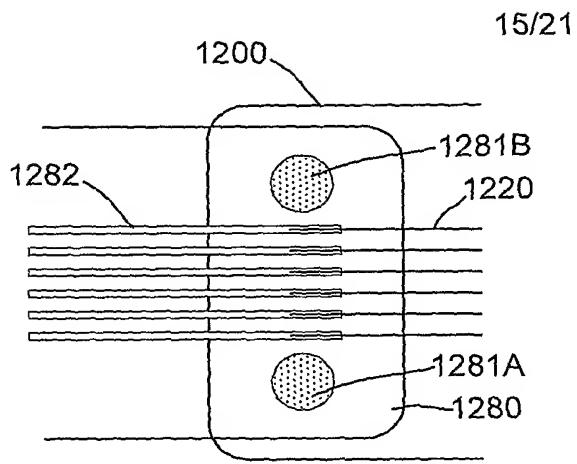
**Fig. 12E**



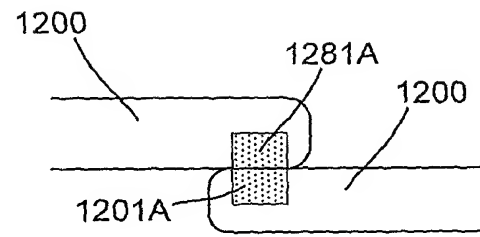
**Fig. 12F**



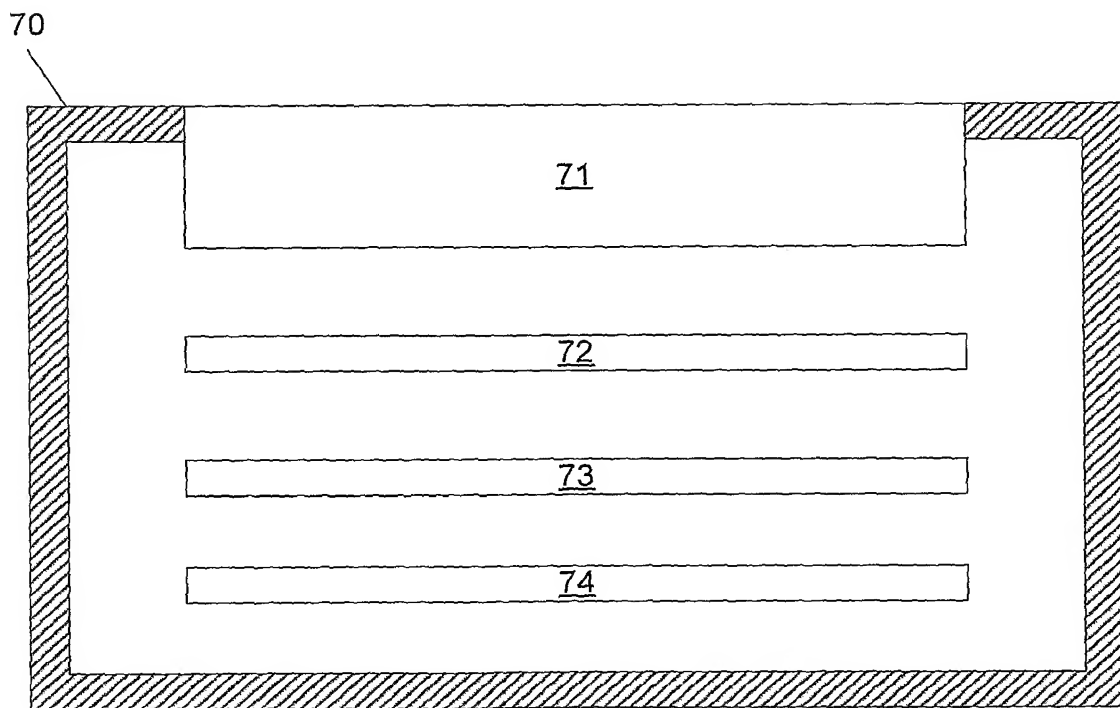
**Fig. 12I**



**Fig. 12G**

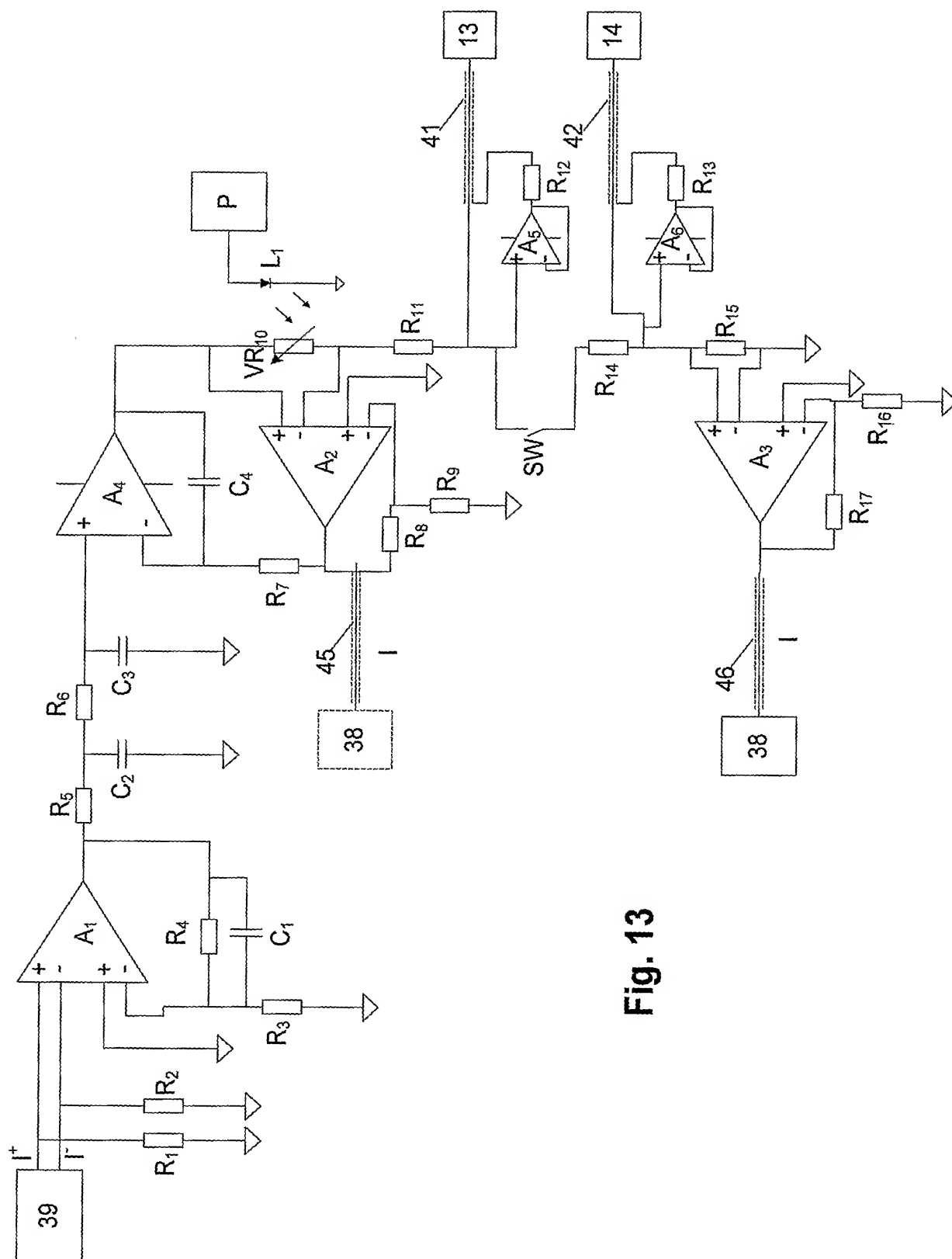


**Fig. 12H**

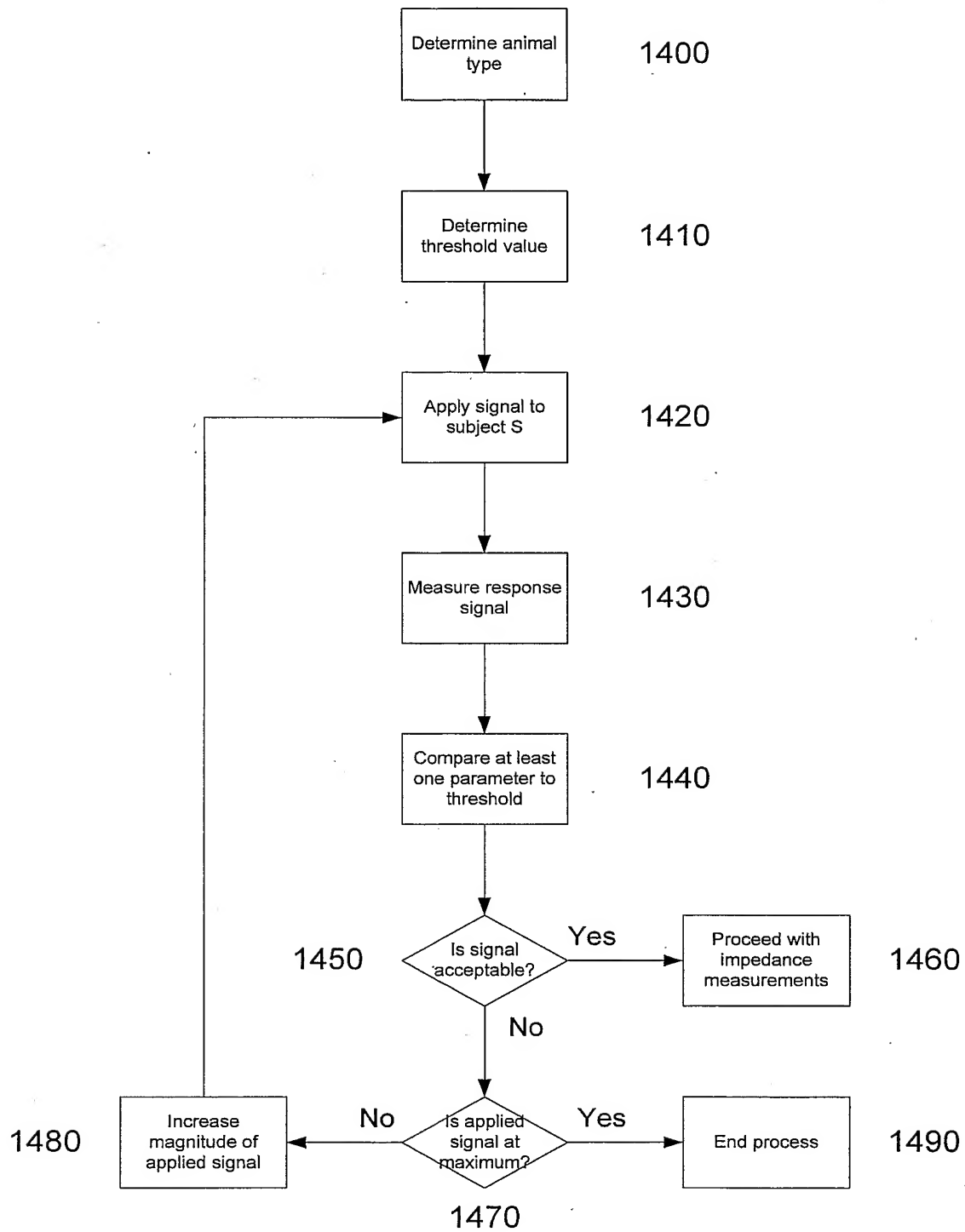


**Fig. 19**

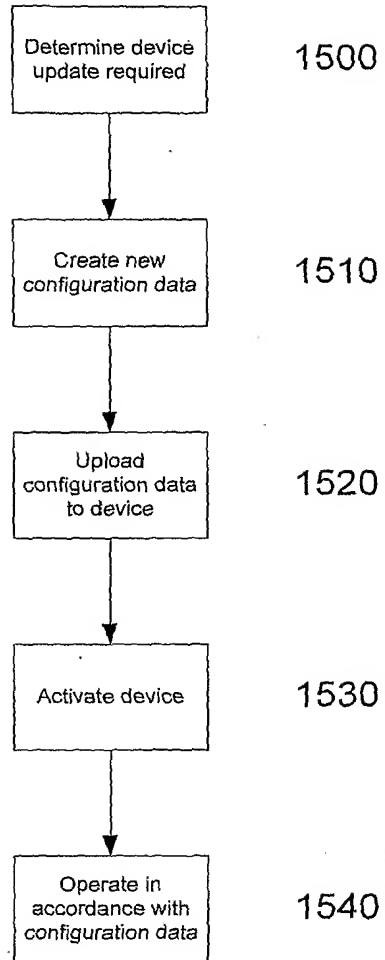
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**Fig. 14**

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**Fig. 15**

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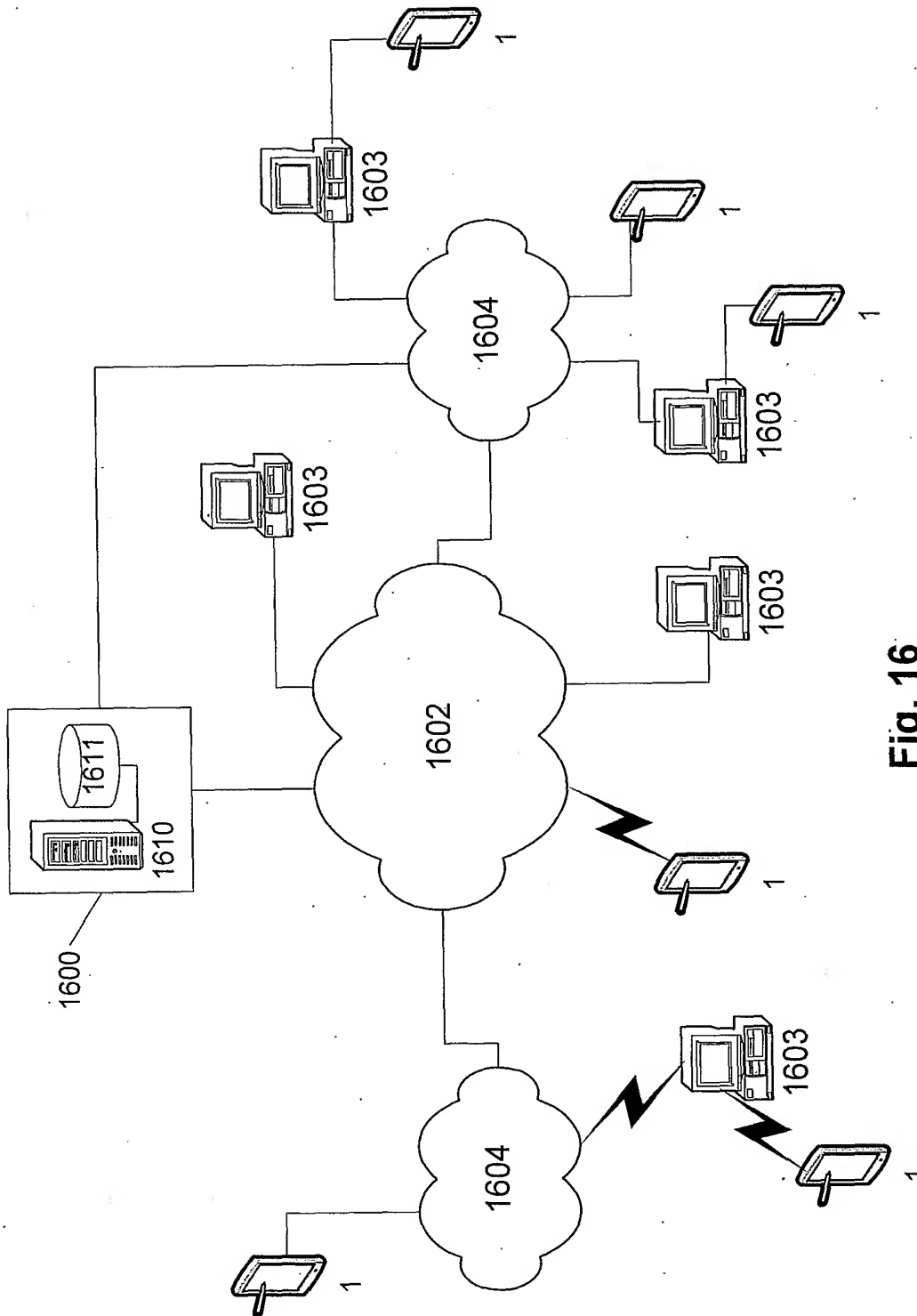
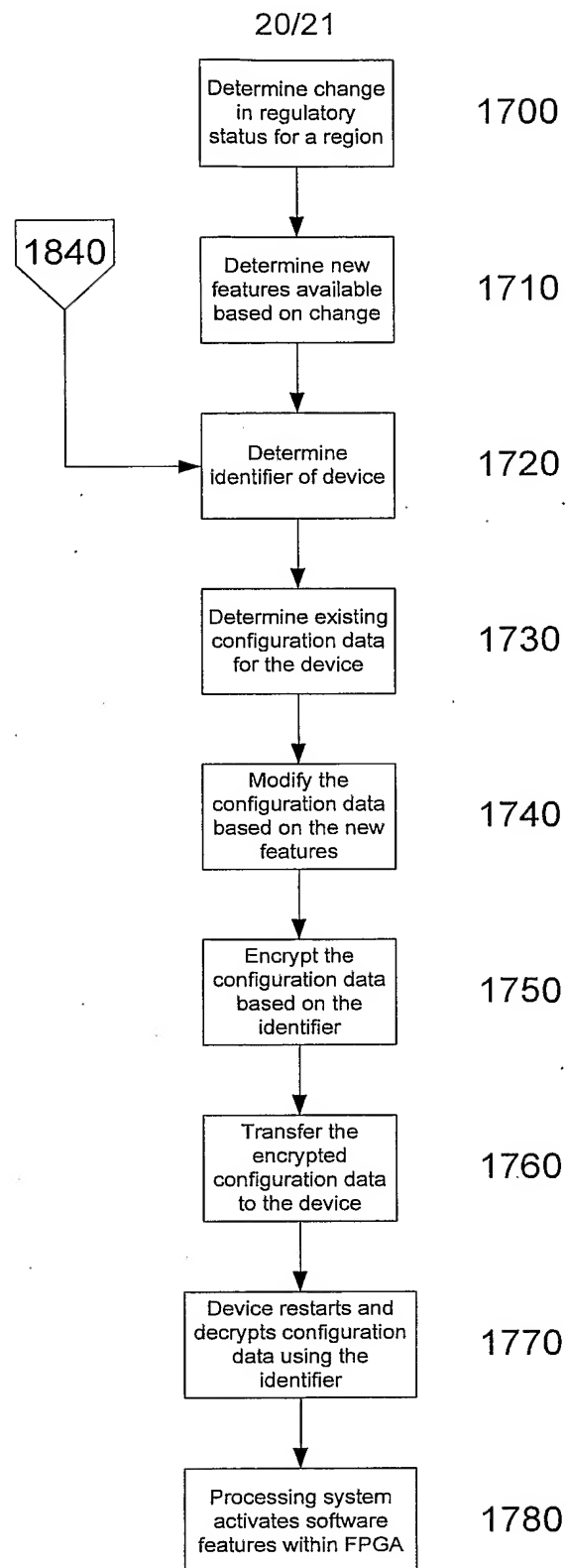
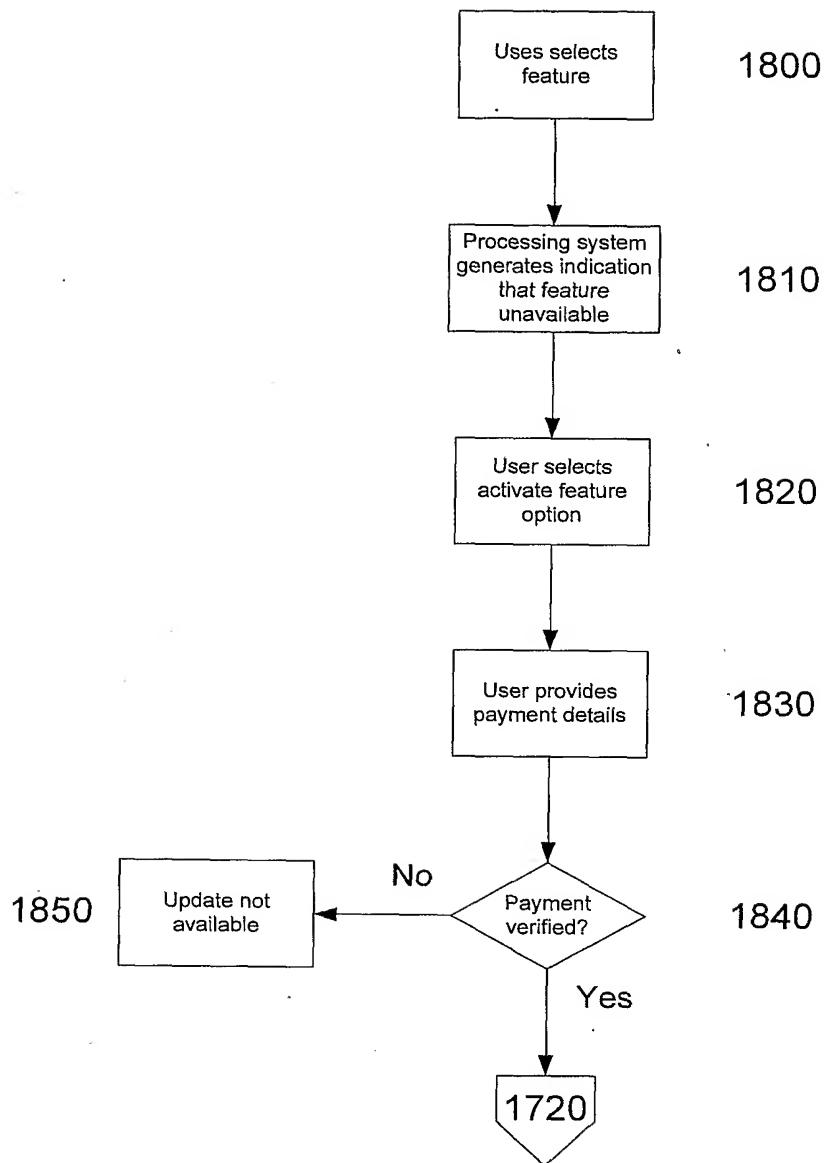


Fig. 16



**Fig. 17**

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**Fig. 18**

## INTERNATIONAL SEARCH REPORT

International application No.

PCT/AU2006/000922

<b>A. CLASSIFICATION OF SUBJECT MATTER</b> Int. Cl. <b>A61B 5/05</b> (2006.01) According to International Patent Classification (IPC) or to both national classification and IPC		
<b>B. FIELDS SEARCHED</b> Minimum documentation searched (classification system followed by classification symbols) Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched Electronic data base consulted during the international search (name of data base and, where practicable, search terms used) DWPI (IPC: A61B ; KEYWORDS: +impedance, +resistance, body, person, +processor+, +computer+, processing, software, program+, instruction+, procedur+, automat+, measure+, test+, evaluat+, determin+, 2nd, second, duo+, dual)		
<b>C. DOCUMENTS CONSIDERED TO BE RELEVANT</b>		
Category*	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
A	US 6633777 B2 (SZOPINSKI) 14 October 2003 See whole document.	
A	US 6292690 B1 (PETRUCELLI et al.) 18 September 2001 See whole document.	
A	US 6256532 B1 (CHA) 3 July 2001 See whole document.	
A	US 6228033 B1 (KÖÖBI) 8 May 2001 See whole document.	
<input checked="" type="checkbox"/> Further documents are listed in the continuation of Box C <input checked="" type="checkbox"/> See patent family annex		
* Special categories of cited documents: "A" document defining the general state of the art which is not considered to be of particular relevance "E" earlier application or patent but published on or after the international filing date "L" document which may throw doubts on priority claim(s) or which is cited to establish the publication date of another citation or other special reason (as specified) "O" document referring to an oral disclosure, use, exhibition or other means "P" document published prior to the international filing date but later than the priority date claimed	"T" later document published after the international filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention "X" document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone "Y" document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art "&" document member of the same patent family	
Date of the actual completion of the international search 10 October 2006		Date of mailing of the international search report 13 OCT 2006
Name and mailing address of the ISA/AU AUSTRALIAN PATENT OFFICE PO BOX 200, WODEN ACT 2606, AUSTRALIA E-mail address: pct@ipaustalia.gov.au Facsimile No. (02) 6285 3929		Authorized officer <b>PETER T. WEST</b> Telephone No : (02) 6283 2108

## INTERNATIONAL SEARCH REPORT

International application No.

PCT/AU2006/000922

C (Continuation). DOCUMENTS CONSIDERED TO BE RELEVANT		
Category*	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
A	US 6011992 A (HUBBARD et al.) 4 January 2000 See whole document.	
A	US 4793362 A (TEDNER) 27 December 1988 See whole document.	

## INTERNATIONAL SEARCH REPORT

International application No.

PCT/AU2006/000922

**Box No. II Observations where certain claims were found unsearchable (Continuation of item 2 of first sheet)**

This international search report has not been established in respect of certain claims under Article 17(2)(a) for the following reasons:

1. ☐ Claims Nos.:  
because they relate to subject matter not required to be searched by this Authority, namely:
  
2. ☐ Claims Nos.:  
because they relate to parts of the international application that do not comply with the prescribed requirements to such an extent that no meaningful international search can be carried out, specifically:
  
3. ☐ Claims Nos.:  
because they are dependent claims and are not drafted in accordance with the second and third sentences of Rule 6.4(a)

**Box No. III Observations where unity of invention is lacking (Continuation of item 3 of first sheet)**

This International Searching Authority found multiple inventions in this international application, as follows:

**See Supplemental Box**

1. ☐ As all required additional search fees were timely paid by the applicant, this international search report covers all searchable claims.
2. ☐ As all searchable claims could be searched without effort justifying additional fees, this Authority did not invite payment of additional fees.
3. ☐ As only some of the required additional search fees were timely paid by the applicant, this international search report covers only those claims for which fees were paid, specifically claims Nos.:
4. ☒ No required additional search fees were timely paid by the applicant. Consequently, this international search report is restricted to the invention first mentioned in the claims; it is covered by claims Nos.: **1 to 27**

**Remark on Protest**

- ☐ The additional search fees were accompanied by the applicant's protest and, where applicable, the payment of a protest fee.
- ☐ The additional search fees were accompanied by the applicant's protest but the applicable protest fee was not paid within the time limit specified in the invitation.
- ☐ No protest accompanied the payment of additional search fees.

**Supplemental Box**

(To be used when the space in any of Boxes I to VIII is not sufficient)

**Continuation of Box No: III (Observations where unity of invention is lacking)**

This International Application does not comply with the requirements of unity of invention because it does not relate to one invention or to a group of inventions so linked as to form a single general inventive concept.

In assessing whether there is more than one invention claimed, I have given consideration to those features which can be considered to potentially distinguish the claimed combination of features from the prior art. Where different claims have different distinguishing features they define different inventions.

This International Searching Authority has found that there are different inventions as follows:

- Claims 1 to 27 define performing impedance measurements on a subject using two processing systems. It is considered that this arrangement of two processing systems comprises a first distinguishing feature
- Claims 28 to 37 and define an apparatus for connecting measurement apparatus to an electrode via an electronic circuit. It is considered that the circuit comprises a second distinguishing feature.
- Claims 38 to 49 and 97 define performing impedance measurements on a subject based on encoded values of associated with electrode leads. It is considered that the encoded value comprises a third distinguishing feature.
- Claims 50 to 58 and 98 define performing measurements on a subject based on identifiers associated with electrodes. It is considered that the identifier comprises a fourth distinguishing feature.
- Claims 78 to 85 and 101 define performing impedance measurements by comparing a parameter of a measured signal to a threshold value. It is considered that the comparison step comprises a fifth distinguishing feature.
- Claims 86 to 96 define an electrode for performing impedance measurements comprising an electrically conductive medium in apertures in an insulating layer, the apertures aligned with contact pads of the electrode. It is considered that this combination of features comprises a sixth distinguishing feature.

PCT Rule 13.2, first sentence, states that unity of invention is only fulfilled when there is a technical relationship among the claimed inventions involving one or more of the same or corresponding special technical features. PCT Rule 13.2, second sentence, defines a special technical feature as a feature which makes a contribution over the prior art.

Each of the abovementioned groups of claims has a different distinguishing feature and they do not share any feature which could satisfy the requirement for being a special technical feature. Because there is no common special technical feature it follows that there is no technical relationship between the identified inventions. Therefore the claims do not satisfy the requirement of unity of invention *a priori*

**INTERNATIONAL SEARCH REPORT**

Information on patent family members

International application No.

**PCT/AU2006/000922**

This Annex lists the known "A" publication level patent family members relating to the patent documents cited in the above-mentioned international search report. The Australian Patent Office is in no way liable for these particulars which are merely given for the purpose of information.

Patent Document Cited in Search Report	Patent Family Member		
US 6633777	AU 5255899	BR 9911866	CA 2336825
	CN 1308504	EP 1094749	HK 1041189
	ID 29282	IL 140719	US 2001049479
	US 2004039296	WO 0001301	ZA 200100970
US 6292690	AU 3928700	WO 0150954	
US 6256532	KR 2001011582		
US 6228033	EP 1014852	WO 9851211	
US 6011992	NONE		
US 4793362	EP 0106867	SE 8202533	WO 8303746
Due to data integration issues this family listing may not include 10 digit Australian applications filed since May 2001.			
END OF ANNEX			